



**Politecnico
di Torino**

Analysis and modelling of the quench experiment on HTS sub- sized cable-in-conduit conductors for fusion applications

Roberto Bonifetto, Roberto Zanino,
Andrea Zappatore

NEMO group, Dipartimento Energia,
Politecnico di Torino, Italy

Outline

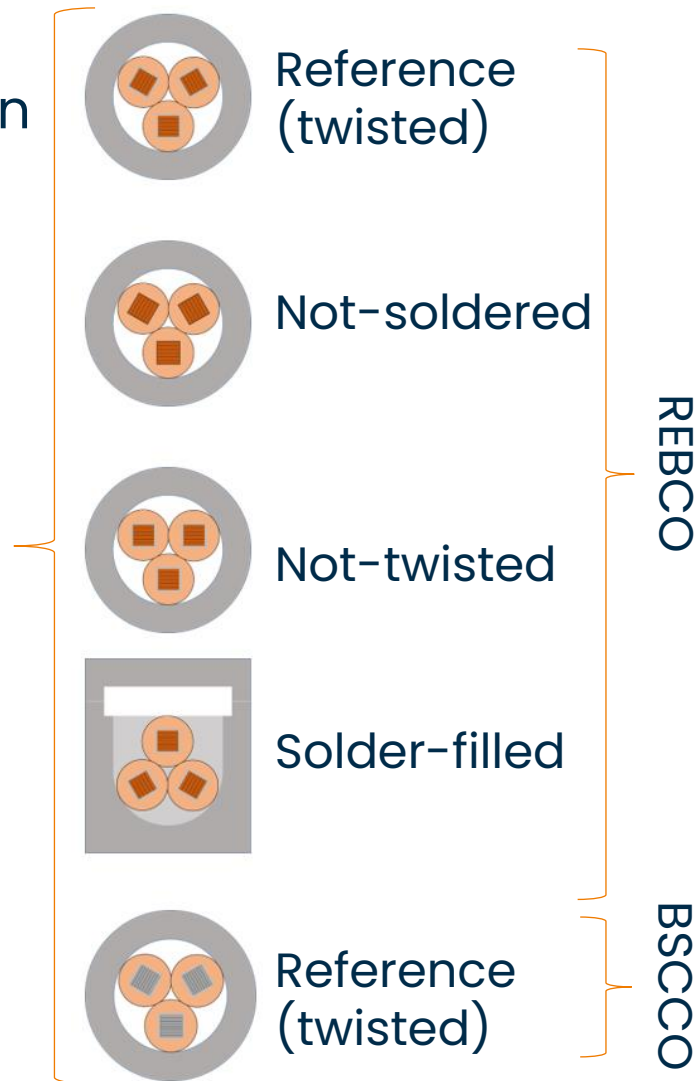
- Introduction & aim
- Experimental setup
- BSCCO conductor
 - Analysis of the experimental data
 - 1D model
- Solder-filled REBCO conductor
 - Analysis of the experimental data
 - 1D model
- Conclusions and perspective

Introduction & aim

- Quench propagation tests in HTS conductors (EU-CN collaboration within EUROfusion Consortium) started in 2020 in SULTAN
- SULTAN was recently upgraded [O. Dicuonzo et al., IEEE TAS, 2021]
- SPC conductors tested in 2020-2021
ENEA and KIT will follow later this year
- Reference and not-twisted conductor already analyzed
[A. Zappatore et al. submitted to Cryogenics]

Aim of this work:

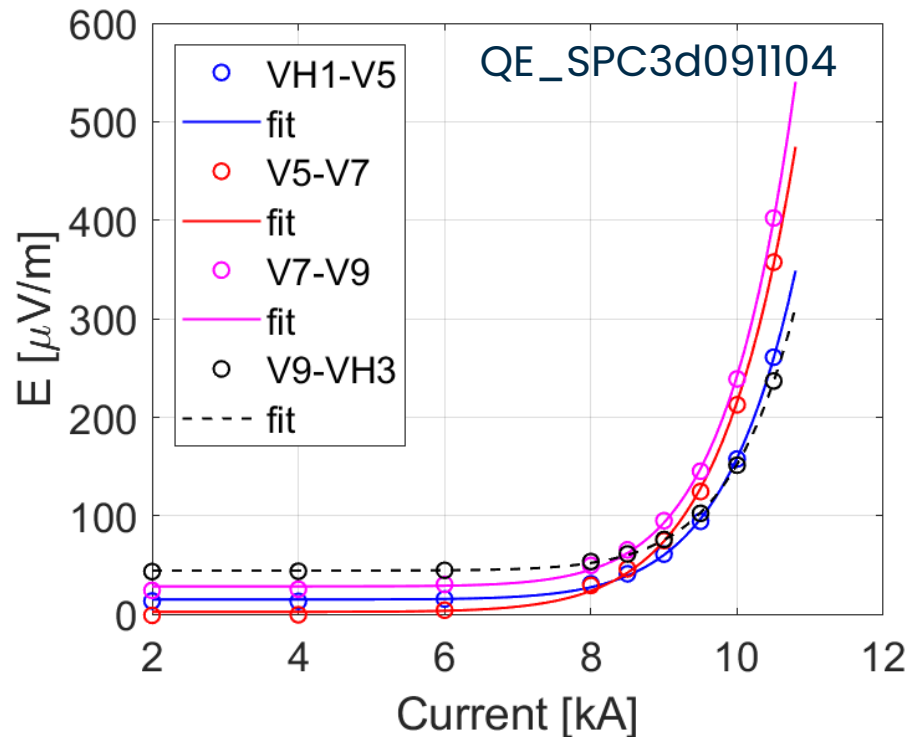
- Analyze the experimental results of BSCCO and solder-filled conductors
- Develop, implement in the H4C code [A. Zappatore et al., SuST, 2020] and validate the corresponding thermal-hydraulic and electric model



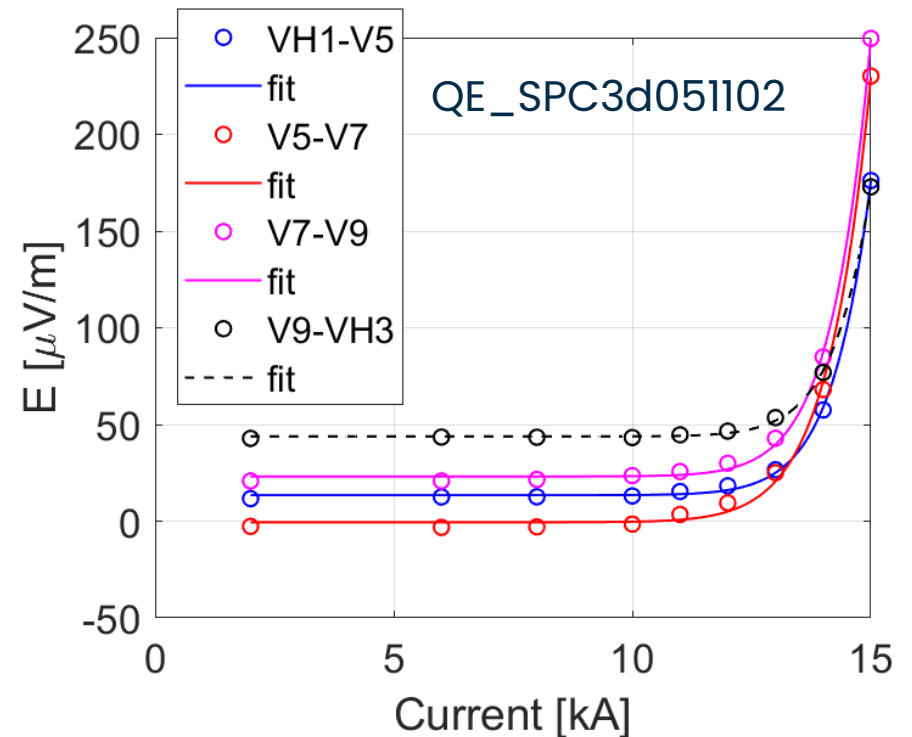
BSCCO conductor – DC performance

- I_C and n-value from fit $E = E_0 + E_C \left(\frac{I}{I_C(B,T)} \right)^n$, $E_C = 100 \mu V/m$
- Lower n-value as magnetic field increases expected from tape measurements [T. Benkel, EPJAP, 2017]

- $I_C(9\text{ T}, 20\text{ K}) = 9.6\text{ kA}$
- n-value = 11.1

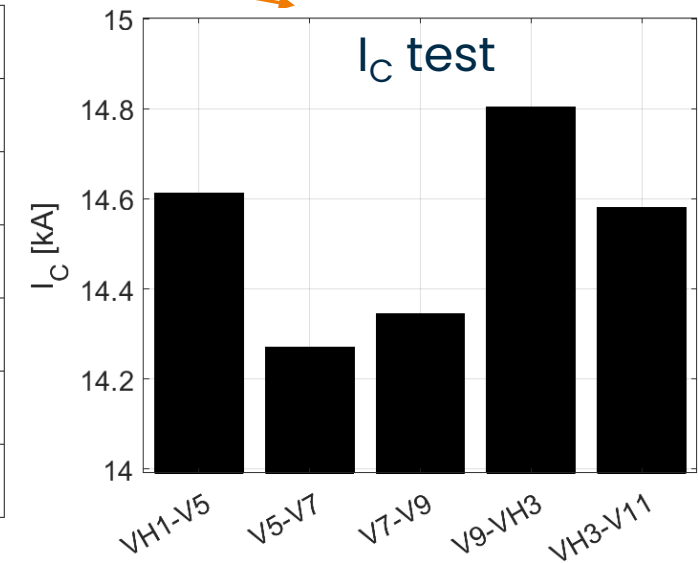
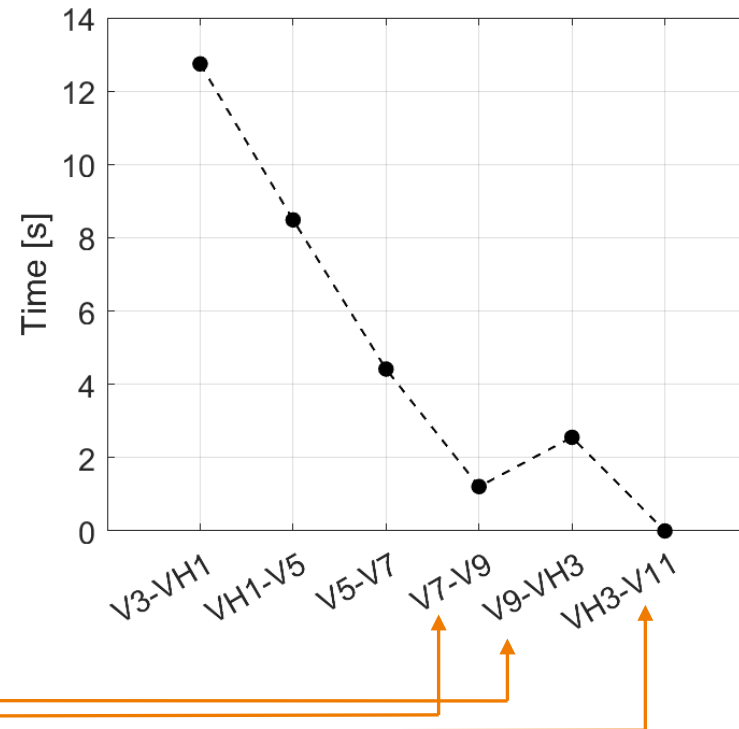
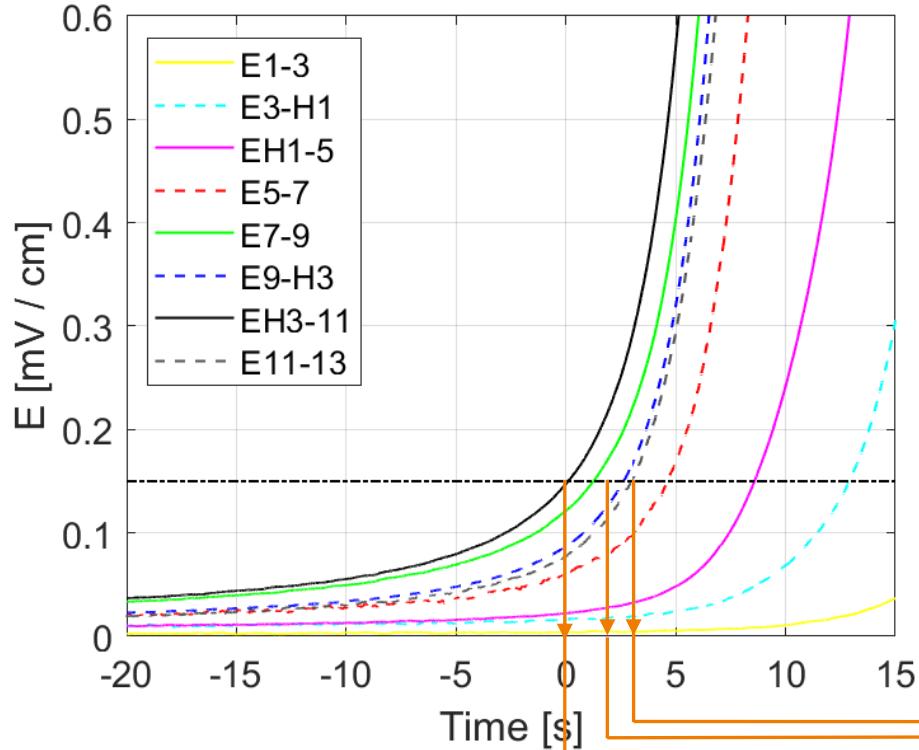


- $I_C(4\text{ T}, 18\text{ K}) = 14.5\text{ kA}$
- n-value = 18.2

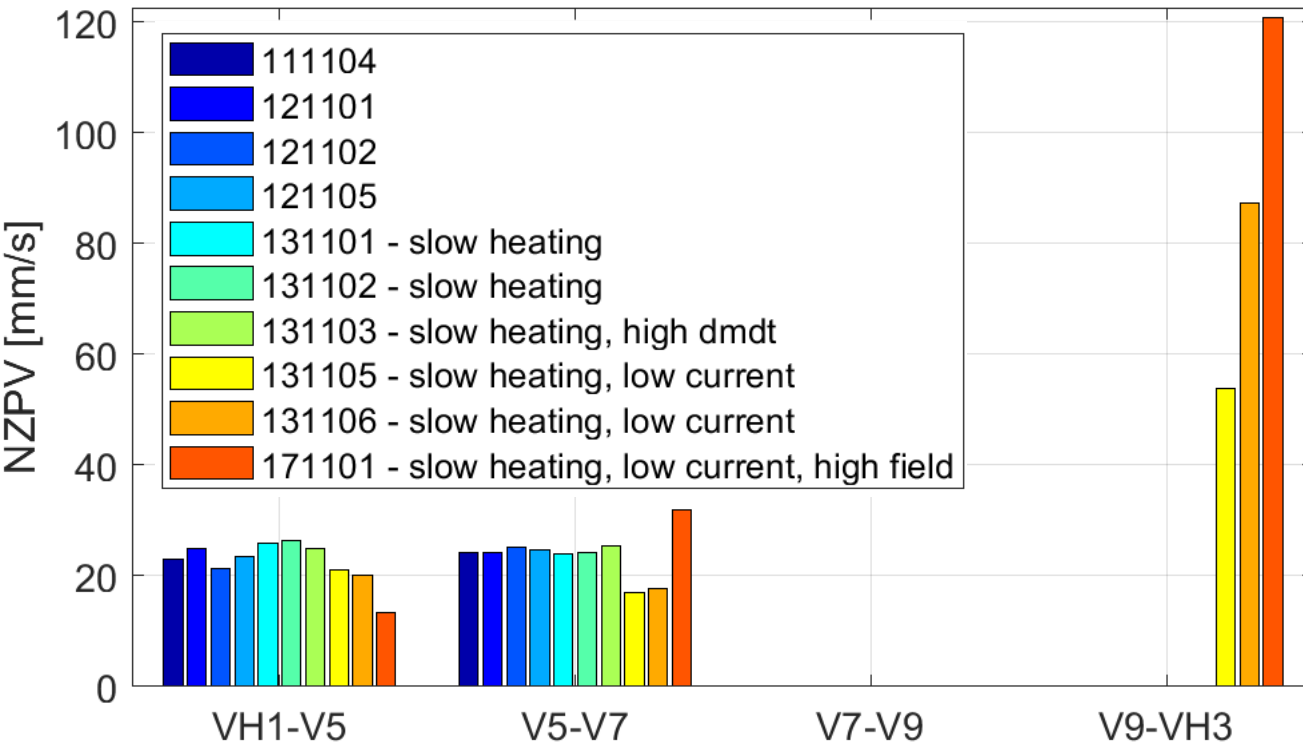


BSCCO conductor – NZPV analysis (I)

In most quench shots, first signal crossing the threshold is VH3-V11, then V7-V9, then V9-VH3 → non-uniform quench propagation close to quench initiation region. Probably due to non-uniformity in $I_C(x)$ → analyzed with numerical model



BSCCO conductor – Normal Zone Propagation Velocity (NZPV) analysis (II)



- NZPV (high J_{Cu}) ~ 20-24 mm/s
- NZPV (low J_{Cu}) ~ 17-20 mm/s
- Slow heating → small impact on NZPV
- NZPV with higher B increases, because margin decreases

BSCCO conductor – Simulation setup

Boundary conditions

Fluid model:

- Inlet temperature: $T1-1(t)$ or $T2-1(t)$
- Inlet and outlet pressure: such that the mass flow rate agrees with the measured one

Thermal model:

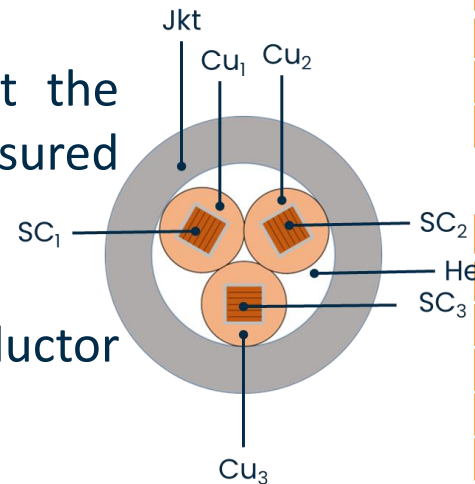
- Zero heat flux (adiabatic) at both conductor ends

Current model:

- Imposed current in SC at conductor outlet
- Zero current gradient at conductor inlet

In case of twisting, the angular dependence of the J_c is taken into account

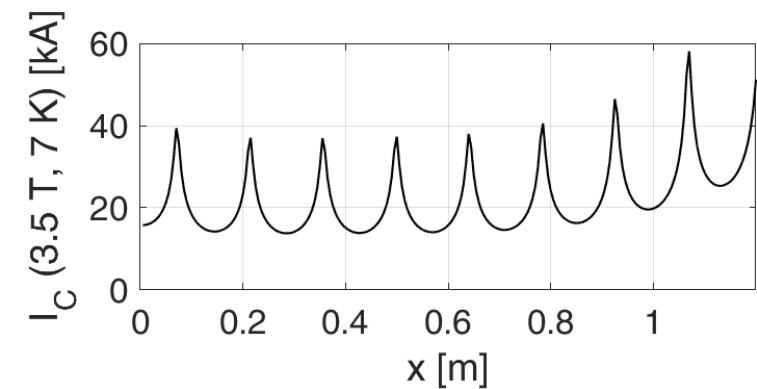
H4C model



Interface parameters & constitutive relations

Electric contact resistance	$[\mu\Omega/m]$
Stack-Copper	0.4
Copper-Copper	8
Copper-Stainless steel	100

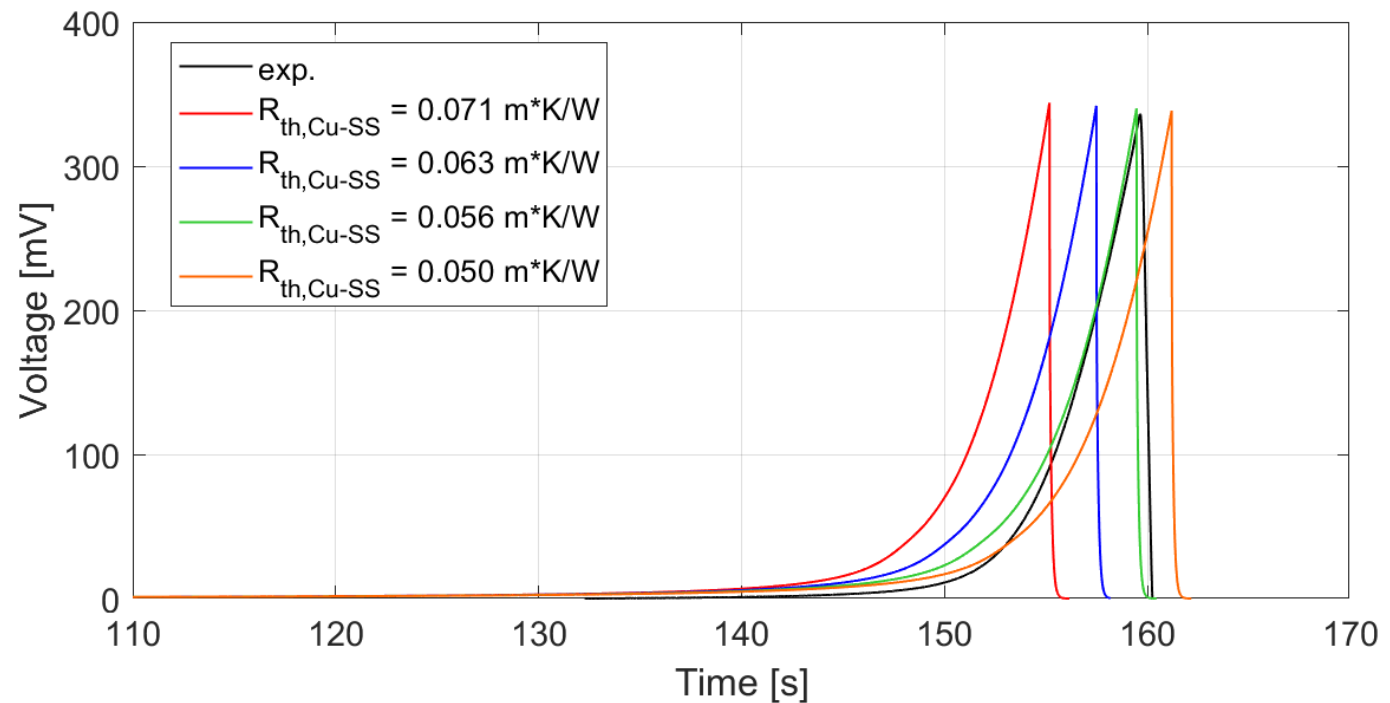
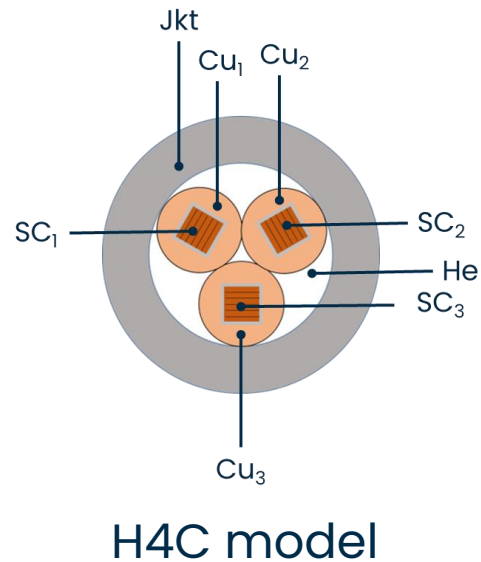
Thermal contact resistance	$[m^2 K/W]$
Stack-Copper	$8 \cdot 10^{-5}$
Copper-Copper	$1 \cdot 10^{-3}$
Copper-Stainless Steel	to be calibrated
Friction factor correlation	Petukhov
Nusselt number correlation	Dittus-Boelter



Electric contact resistances from [N. Bykovskiy,2017], [A. Zappatore, 2021], [M. Vogler, 1993]
 Thermal contact resistances from [Y. A. Cengel, Fundamentals of Thermal-Fluid Sciences, 2017]

BSCCO conductor – Calibration of $R_{th, Cu-SS}$

- Availability of thick jacket thermal capacity depends on $R_{th, Cu-SS}$
- Same ballpark of non-twisted and reference conductors $R_{th, Cu-SS} = 0.083 \text{ K m/W}$ (slightly lower here) as well as measurement done at KIT [0.05 – 0.25 K m/W] [N. Bagrets et al., IEEE TAS, 2022]

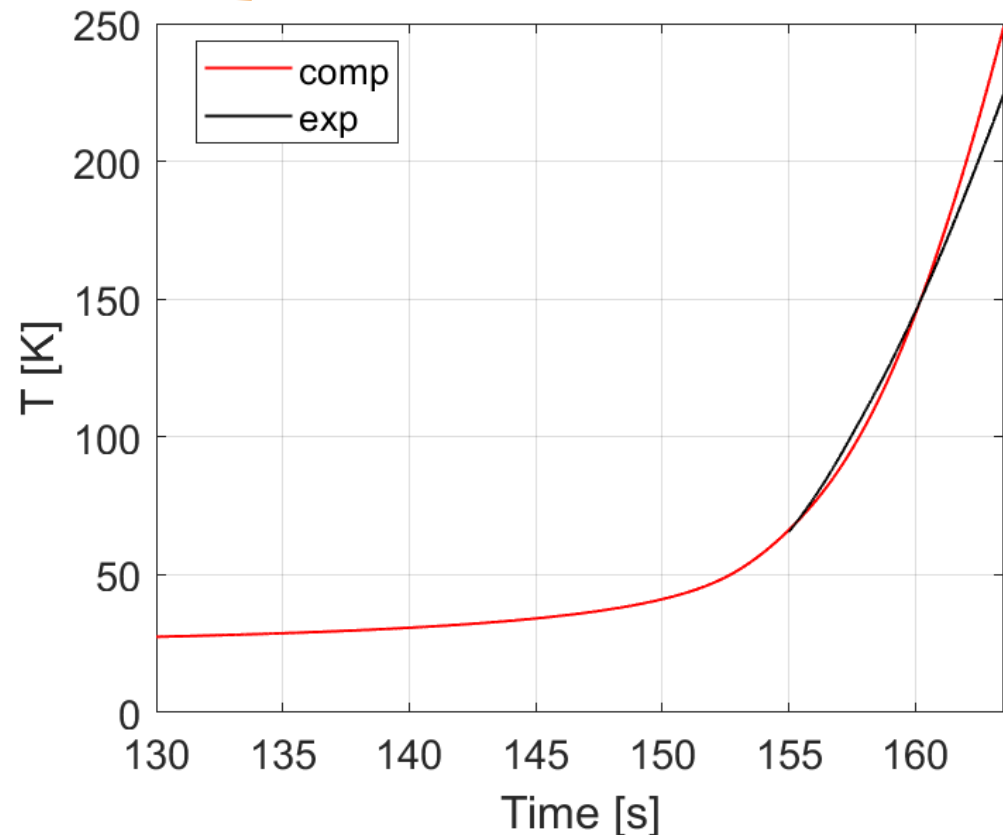
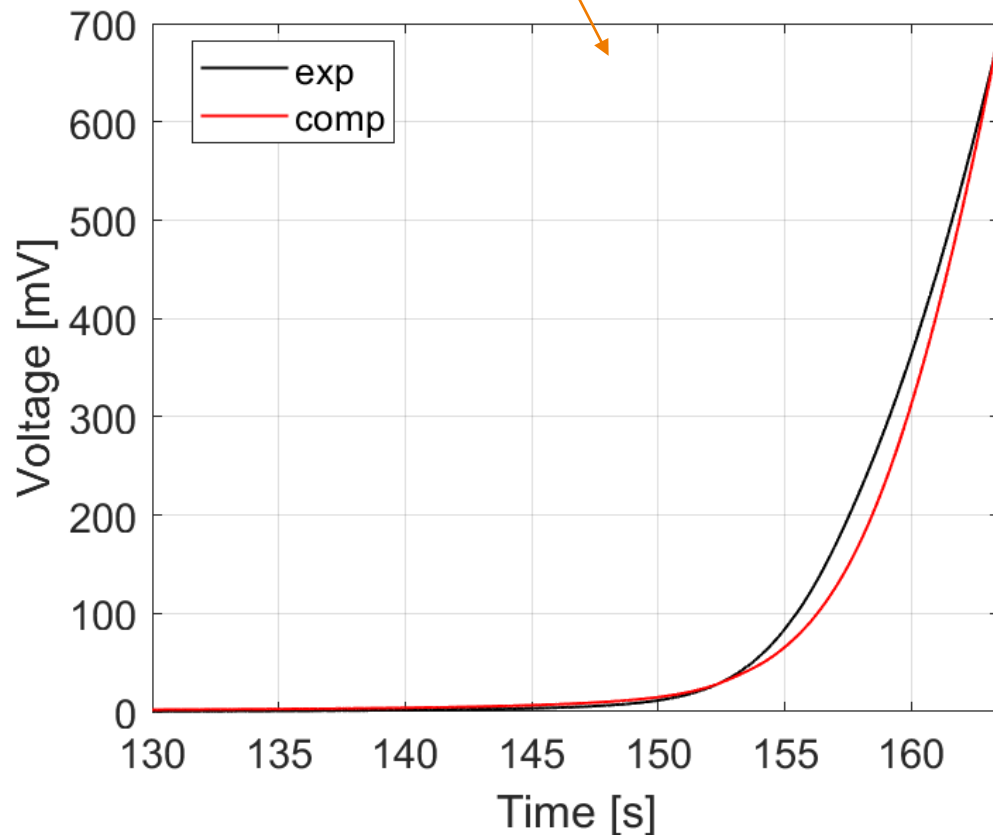


Contact length assumed equal to 2 mm

BSCCO conductor – high J_{Cu} (I)

- Calibrated parameter kept constant
- Experimental hotspot temperature is evaluated assuming all the current is flowing in Cu and jacket
- Good agreement on total voltage and hotspot temperature

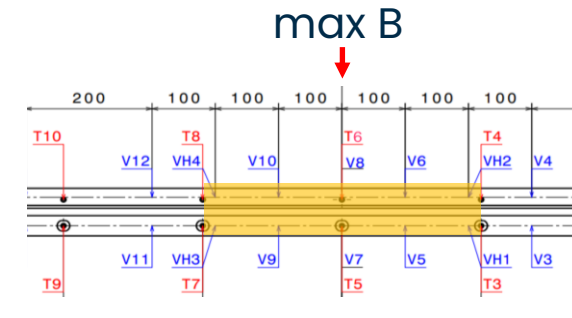
121105 (BSCCO)
4 T, 15 kA
Dump at **135 K**



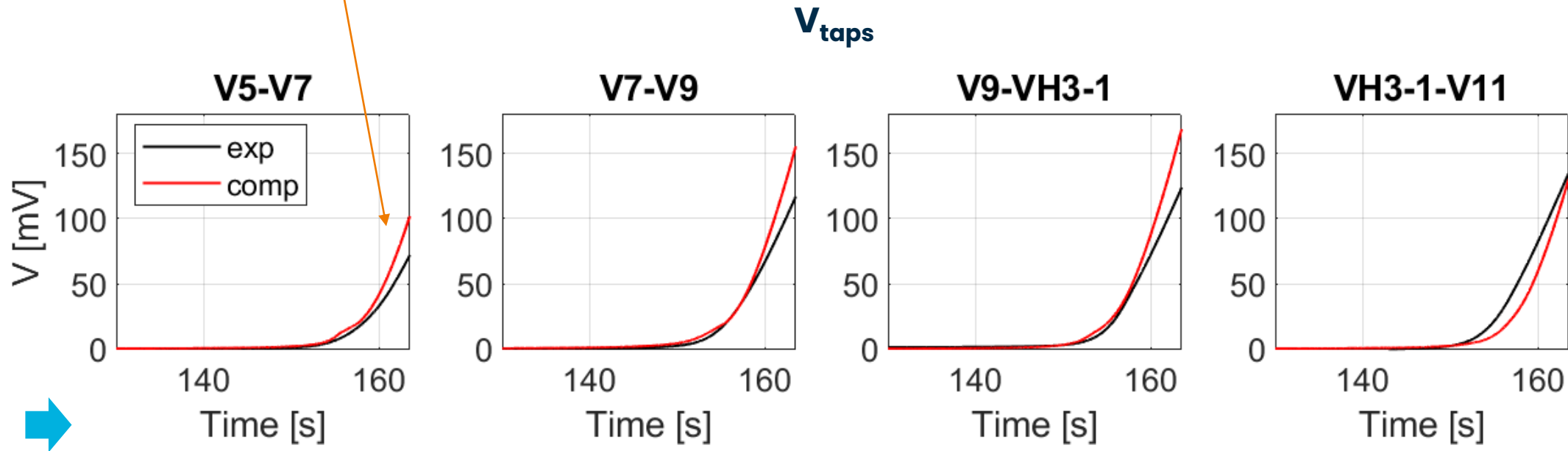
BSCCO conductor – high J_{Cu} (II)

Voltage rise at local level is

- reproduced correctly in terms of spatial distribution (i.e., max V is in V7-V9, V9-VH3)
- but is faster above 50 mV \rightarrow impact of $J_C(x)$ discussed later



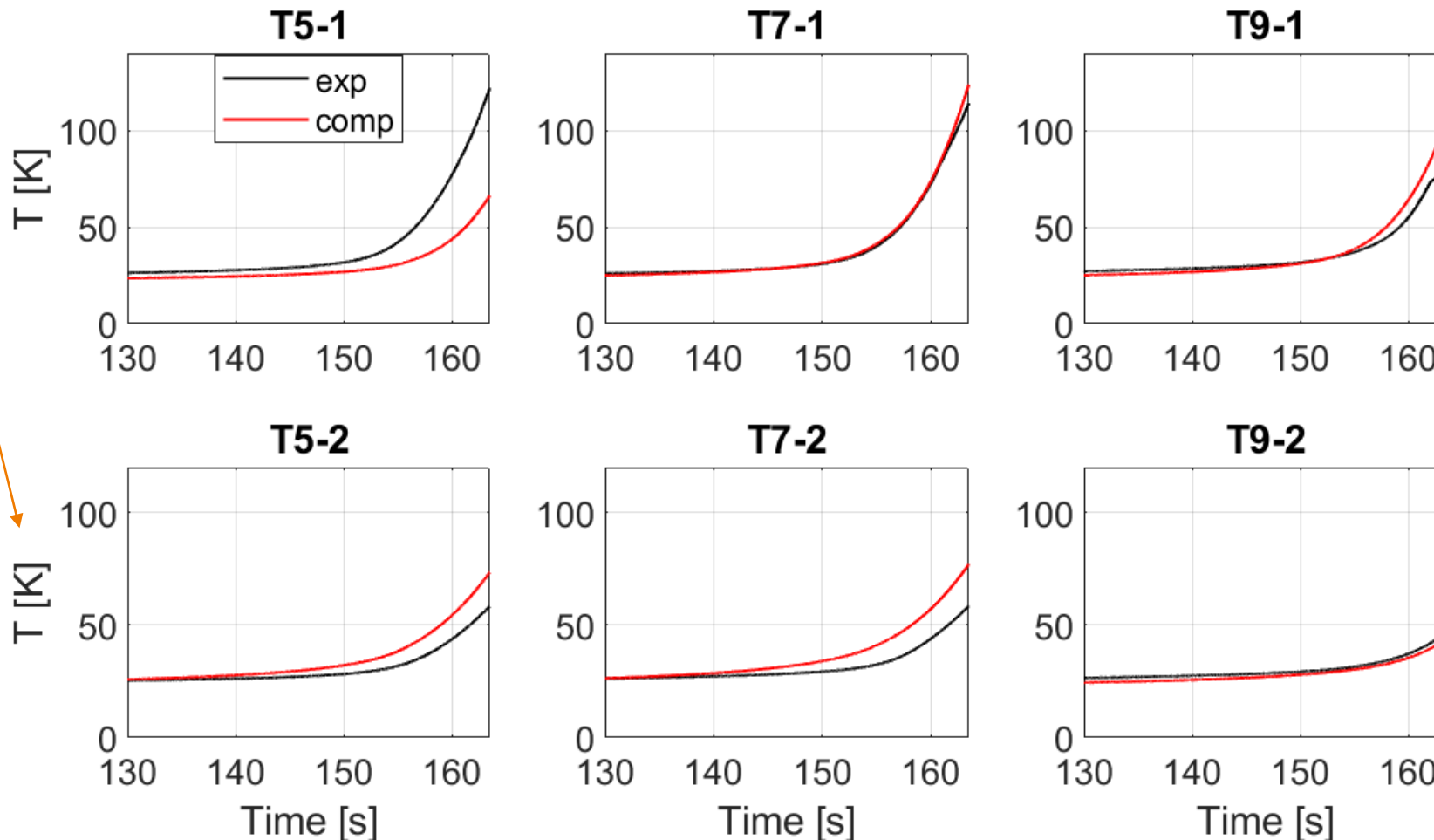
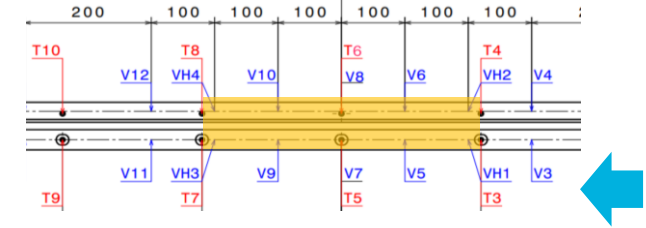
121105 (BSCCO)
4 T, 15 kA
Dump at **135 K**



BSCCO conductor – high J_{Cu} (III) max B

Temperature rise at local level is

- reproduced correctly in terms of maximum value (T7-1)
- slightly overestimated on the jacket \rightarrow impact of jacket discretization discussed later

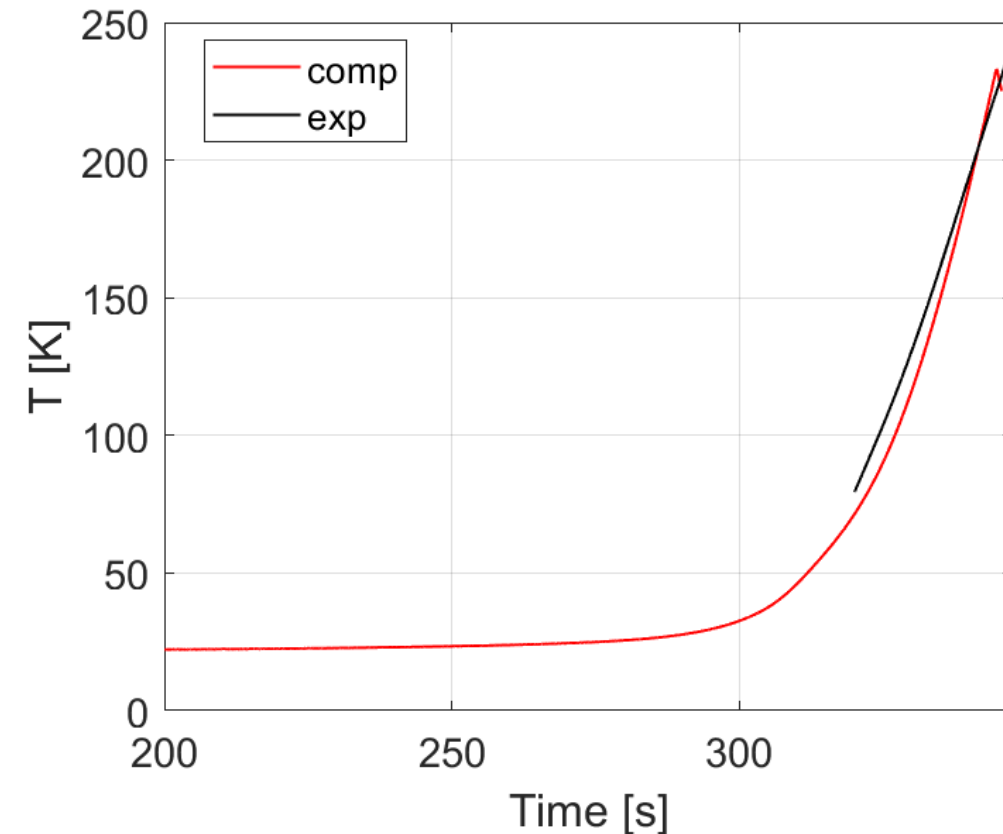
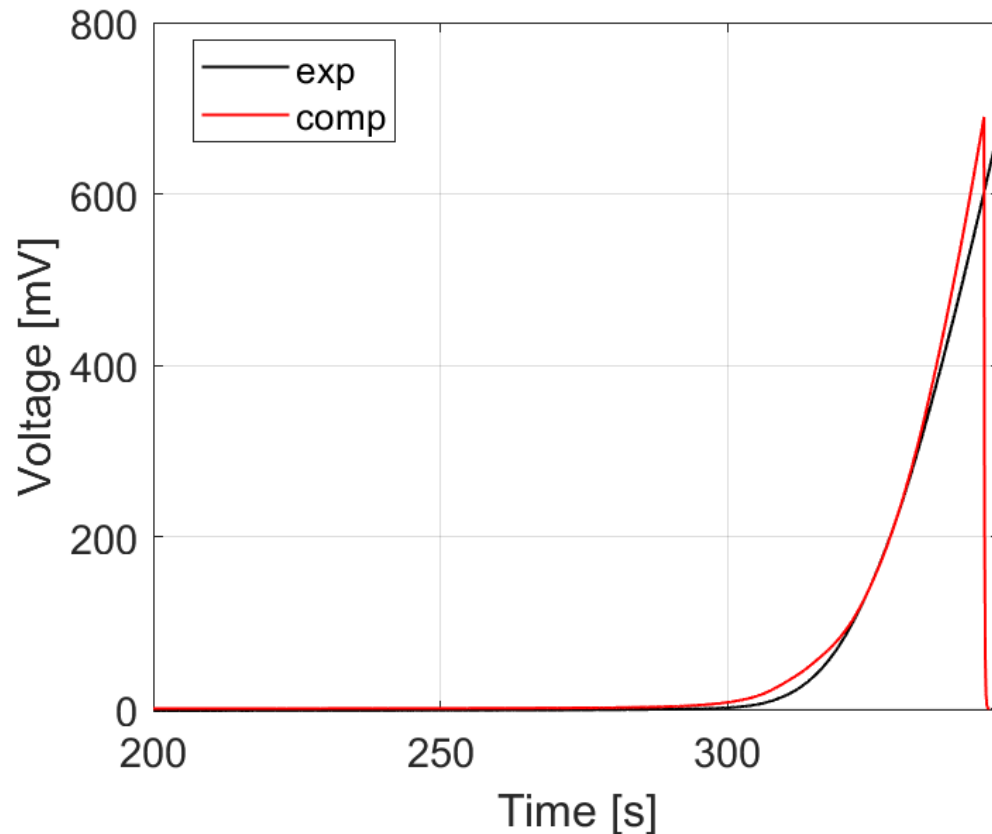


121105 (BSCCO)
4 T, 15 kA
Dump at **135 K**

BSCCO conductor – low J_{Cu} (I)

171101 (BSCCO)
9 T, 9.5 kA
Dump at 160 K

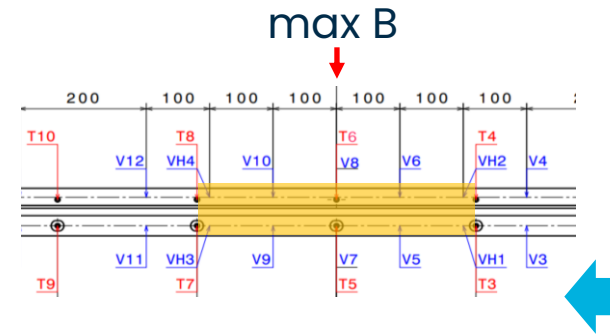
- Calibrated parameters same as before
- Faster voltage rise is evident in this case also on the total voltage



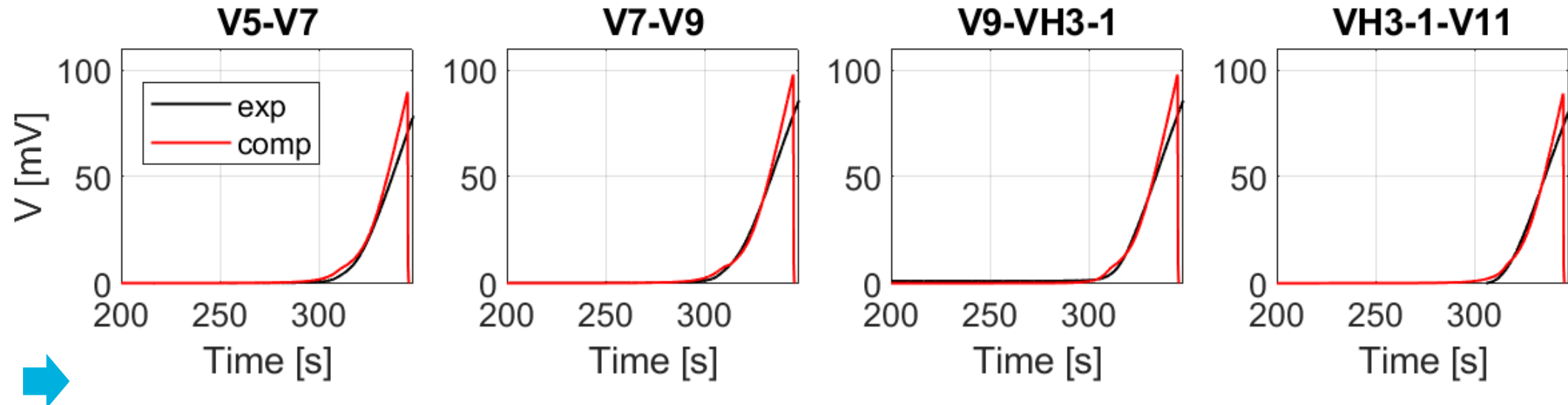
BSCCO conductor – low J_{Cu} (II)

Voltage and temperature rise at local level are well reproduced

Better agreement than in 121105 because here slow heating
→ slower evolution of the transient → easier to capture



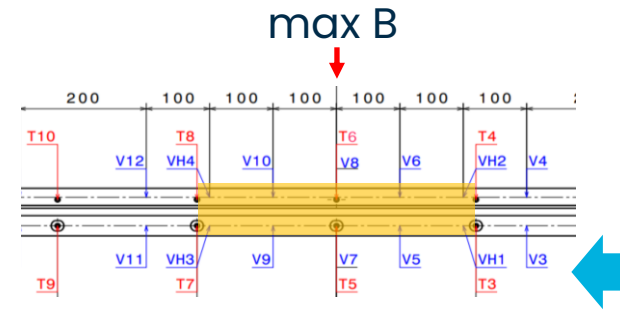
171101 (BSCCO)
9 T, 9.5 kA
Dump at **160 K**



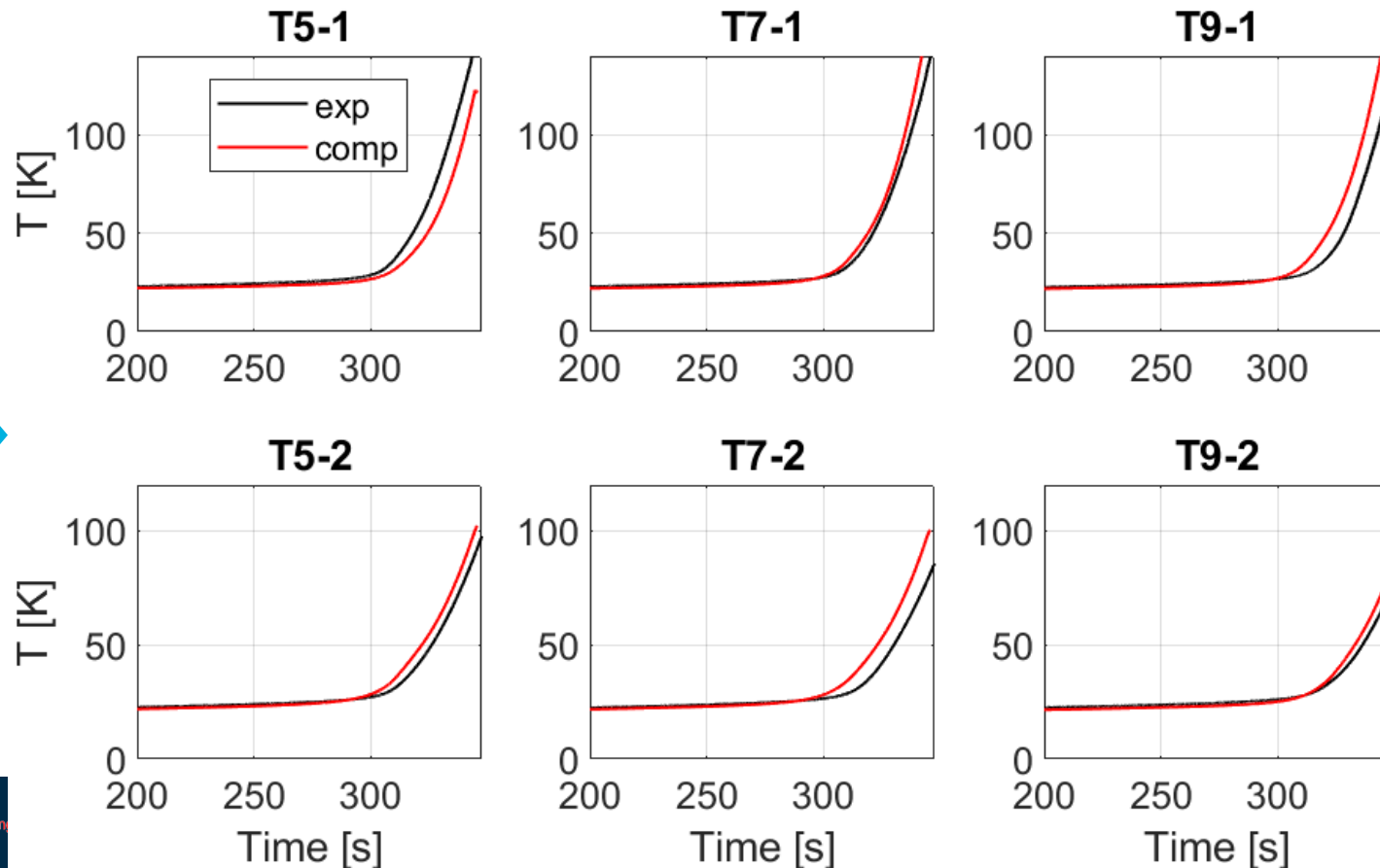
BSCCO conductor – low J_{Cu} (III)

Voltage and temperature rise at local level are well reproduced

Better agreement than in 121105 because here slow heating → slower evolution of the transient → easier to capture



171101 (BSCCO)
9 T, 9.5 kA
Dump at **160 K**

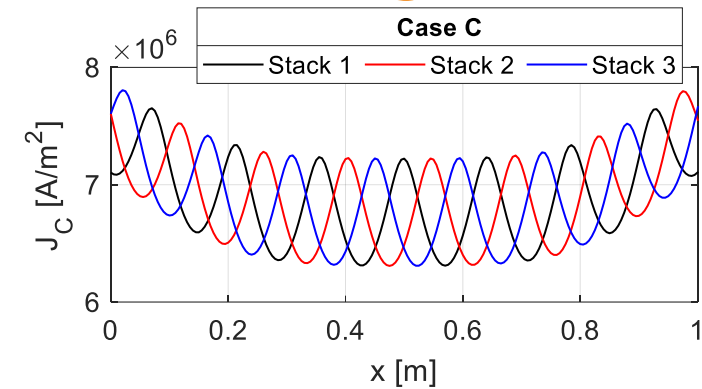
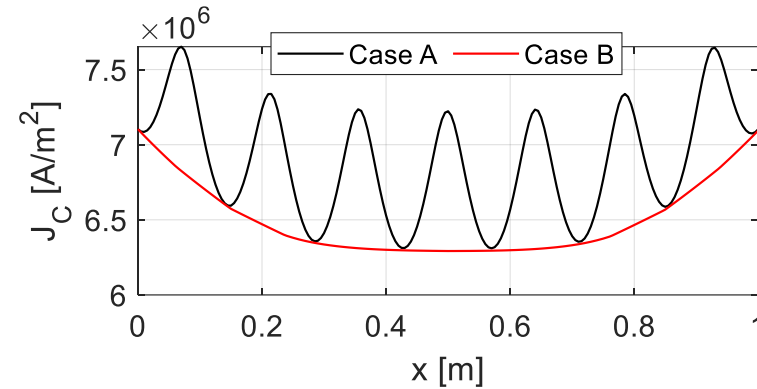


BSCCO conductor – Effect of twisting

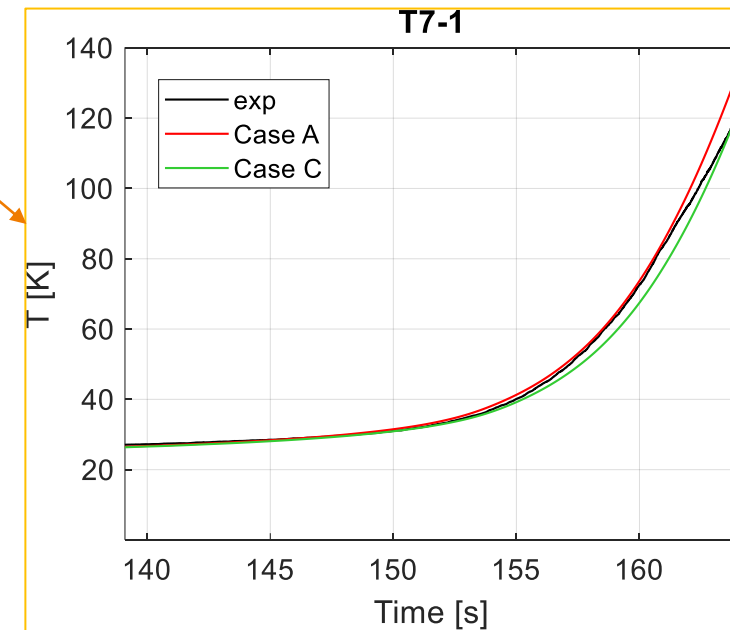
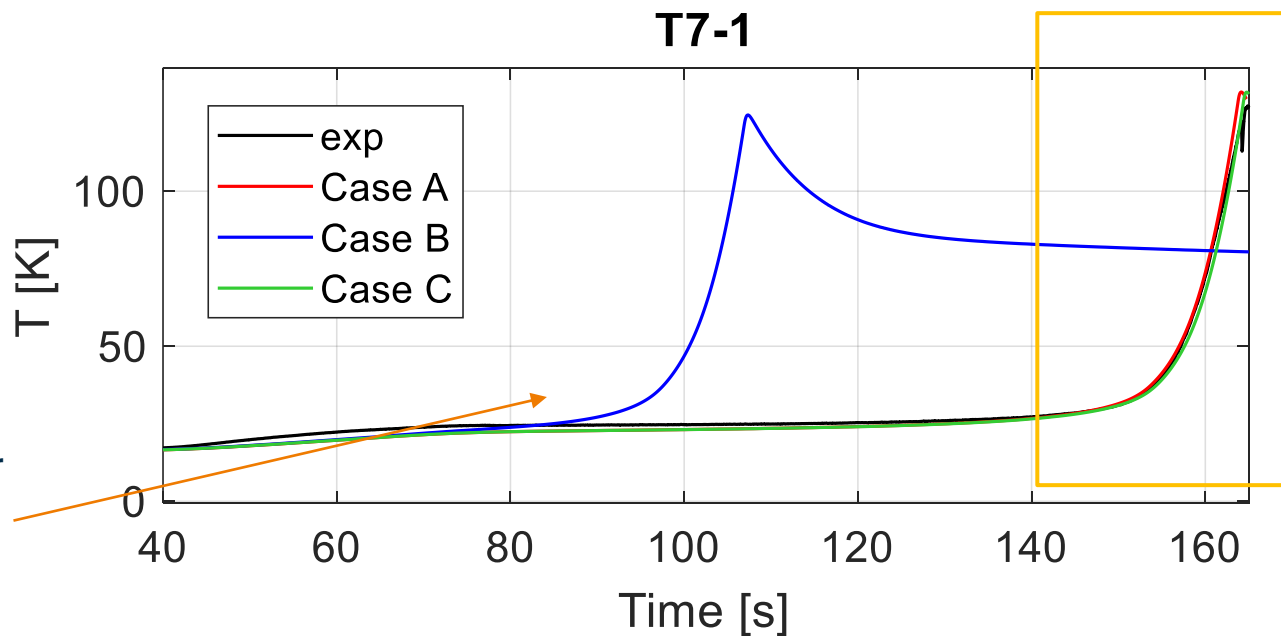
Case A: start angles = $[0, 0, 0]$

Case B: no twisting

Case C: start angles = $[0, 120, 240]$



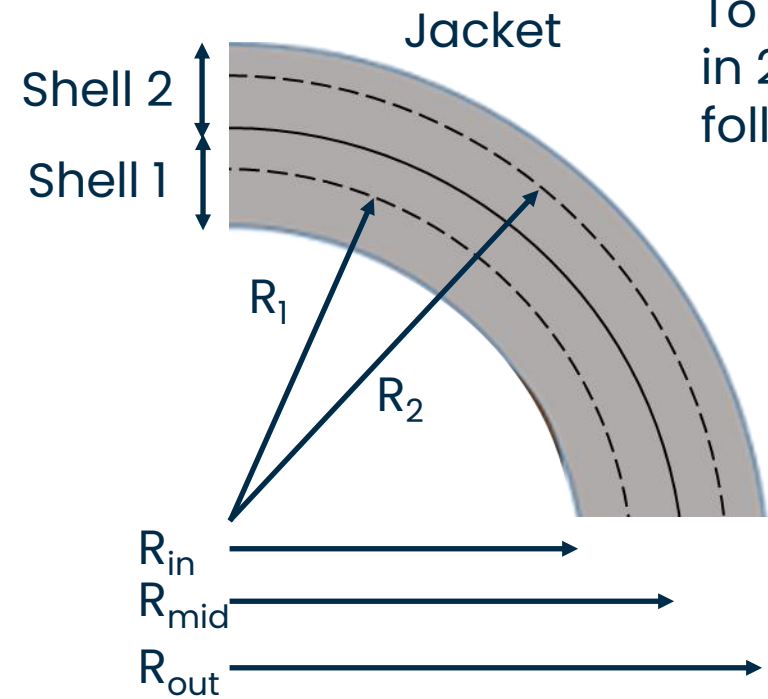
- If twisting is considered, start angles have negligible effect on the results
- If twisting is not considered, “average” I_C is lower → quench initiation is strongly anticipated



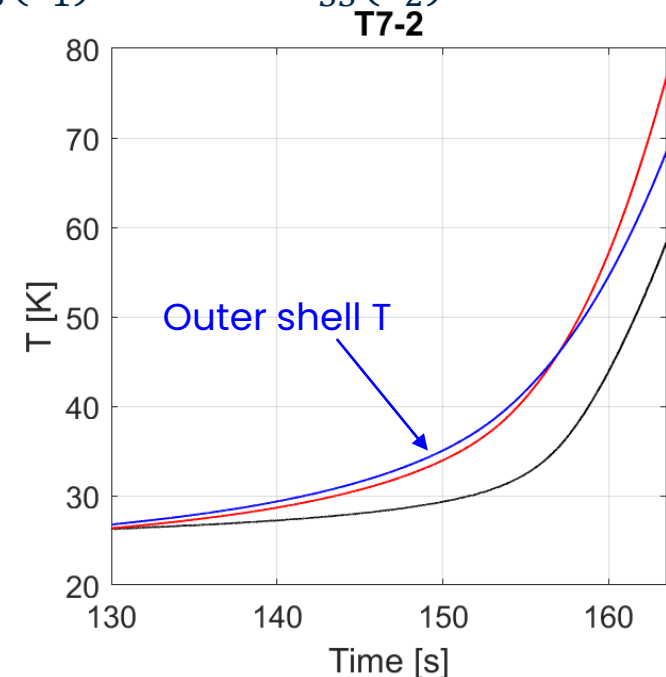
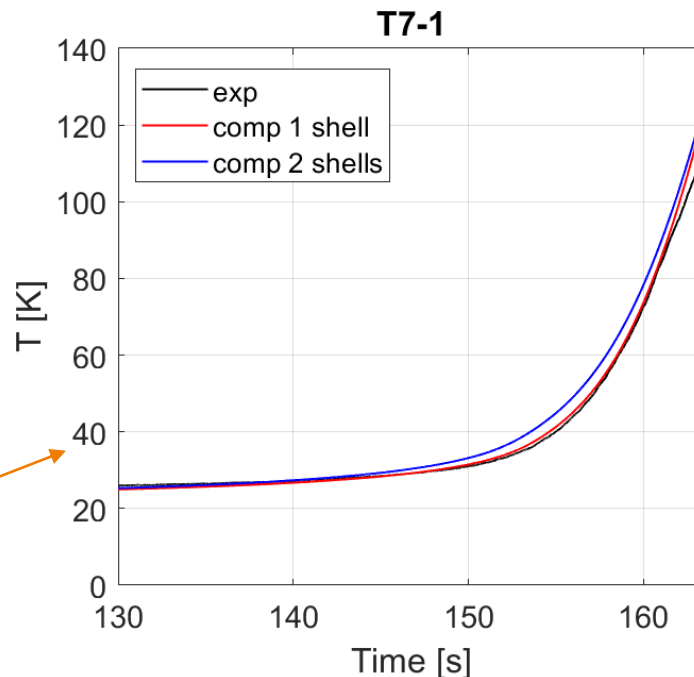
BSCCO conductor – Effect of jacket radial discretization

To account for non negligible diffusion time (wrt quench time scale) → split in 2 shells (lumped in R_1 and R_2) the jacket discretization, connected by the following resistance:

$$R_{SS_1-SS_2} = \frac{1}{\frac{D_{in} \log\left(\frac{D_{mid}}{D_{in}}\right)}{2k_{SS}(T_1)} + \frac{D_{in} \log\left(\frac{D_{out}}{D_{mid}}\right)}{2k_{SS}(T_2)}}$$

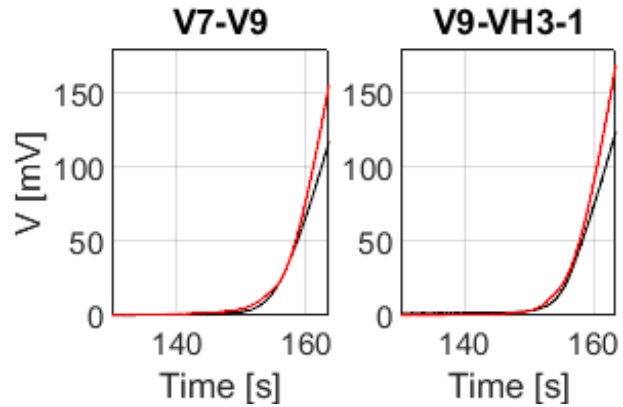


After recalibration of $R_{th,CU-SS}$, negligible effect on T_{He}

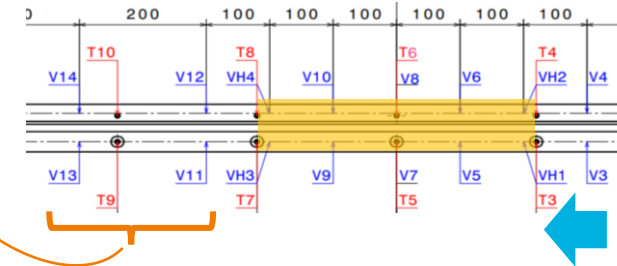
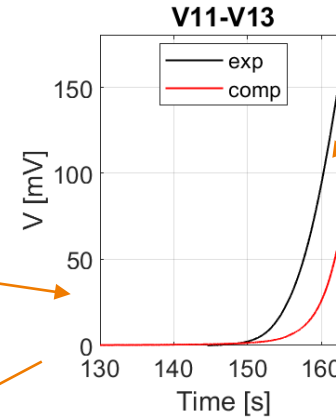


~ 10 K decrease in T_{jacket} if 2 shells are considered

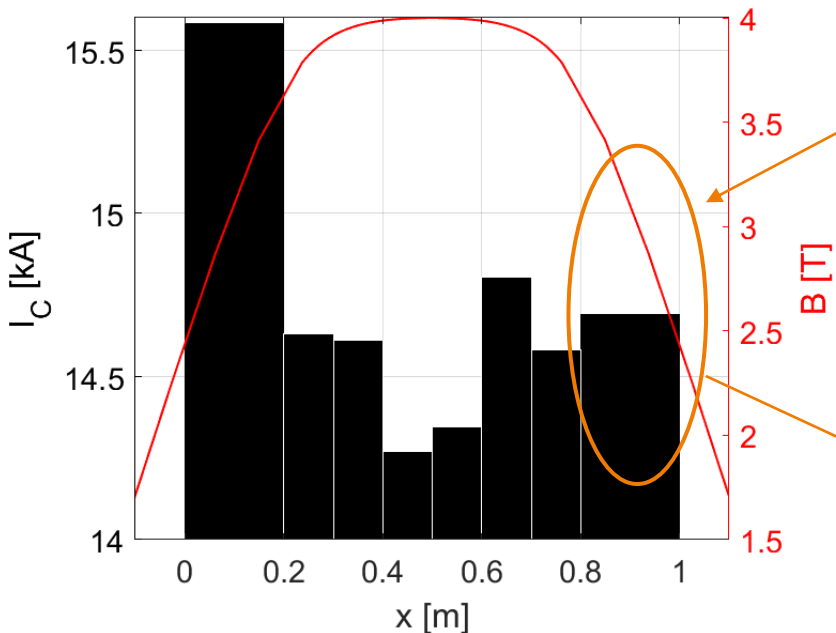
BSCCO conductor – Effect of $J_C(x)$ (I)_{max B}



Comp. V rises faster than exp. in HFZ → check in low B region → behavior is reversed

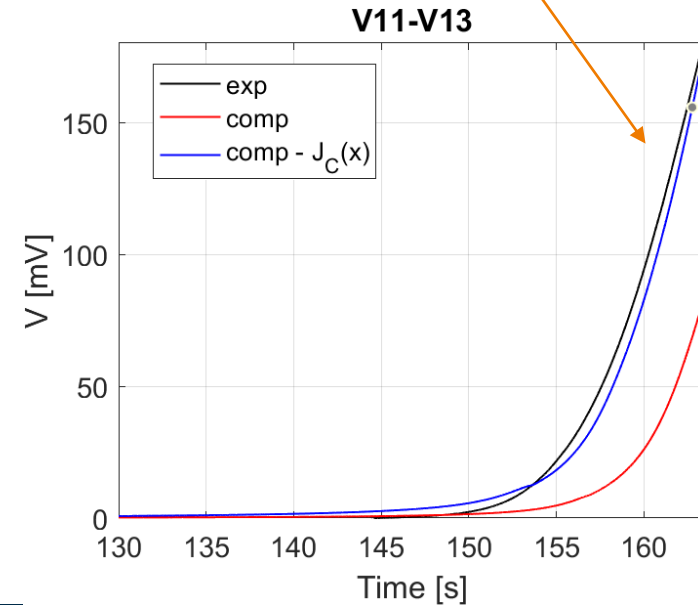


Check DC performance (I_C)



$I_C(3.5-2.5 \text{ T}) \sim I_C(4 \text{ T})$
→ ~5% degradation in $x=[0.8 \text{ } 1.0] \text{ m}$

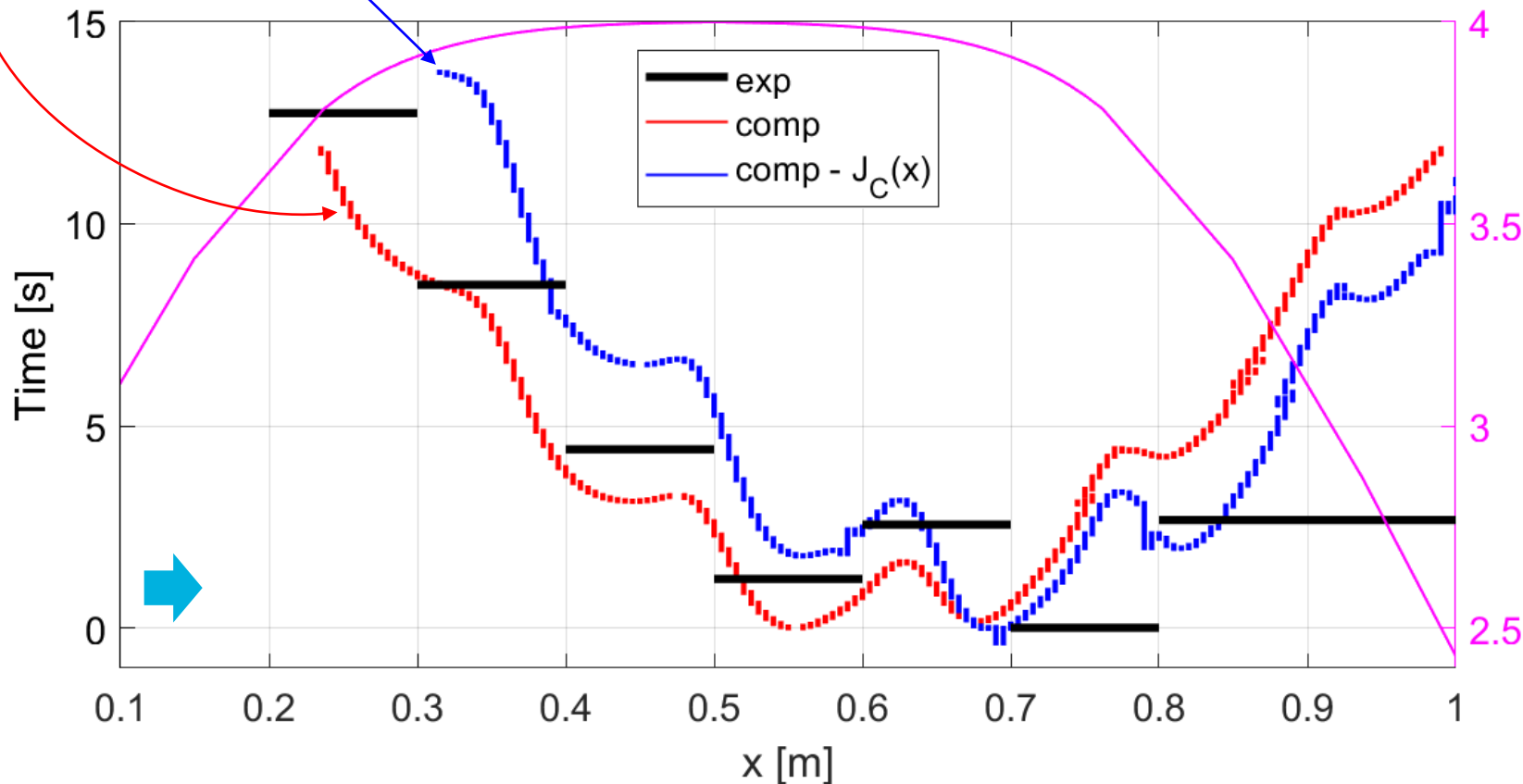
Accounting for $J_C(x)$ strongly improves agreement



BSCCO conductor – Effect of $J_C(x)$ (II)

Mark NZ front when $E = 15$ mV/cm

- If no info on J_C degradation \rightarrow symmetric propagation wrt $x = 0.63$ m
- If $J_C(x)$ accounting for degradation \rightarrow (average) measured $E(x)$ is better reproduced



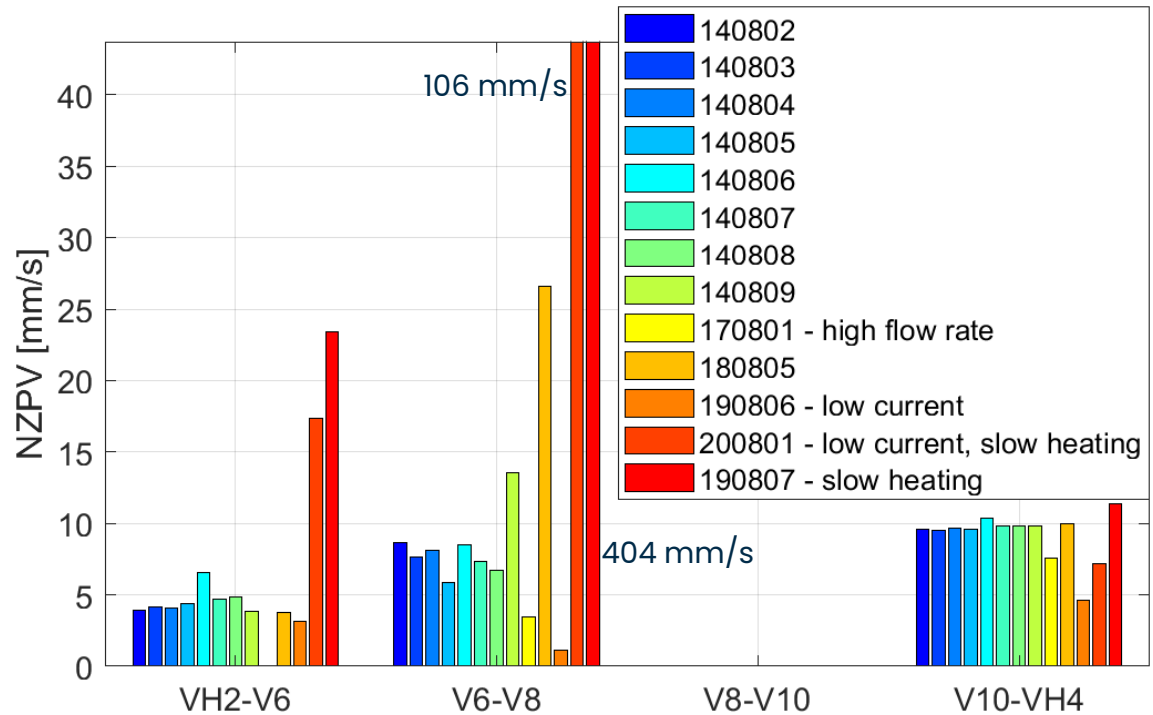
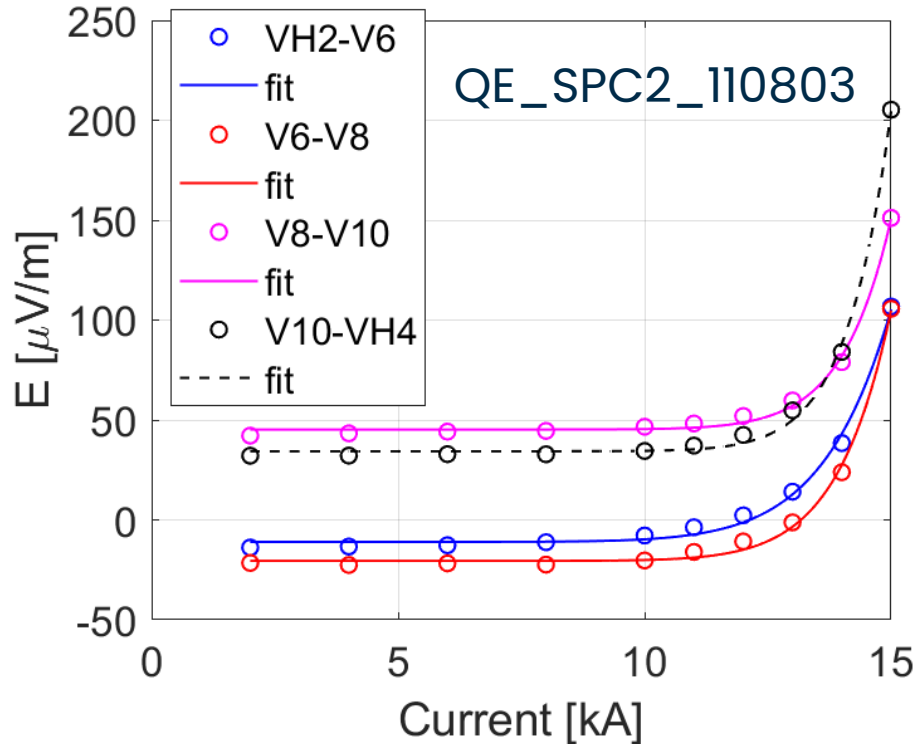
- Initiation in $x = [0.7-0.8]$
- Symmetric propagation wrt $x = [0.7-0.8]$
- $E = 15$ mV/cm in $x = [0.7-0.8]$ before than in $x = [0.5-0.6]$

Solder-filled REBCO conductor

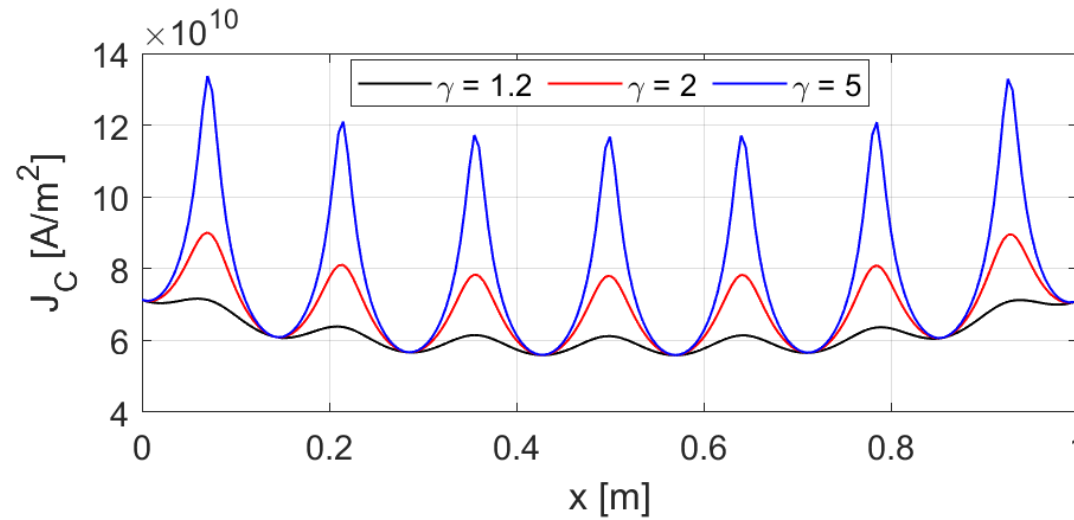
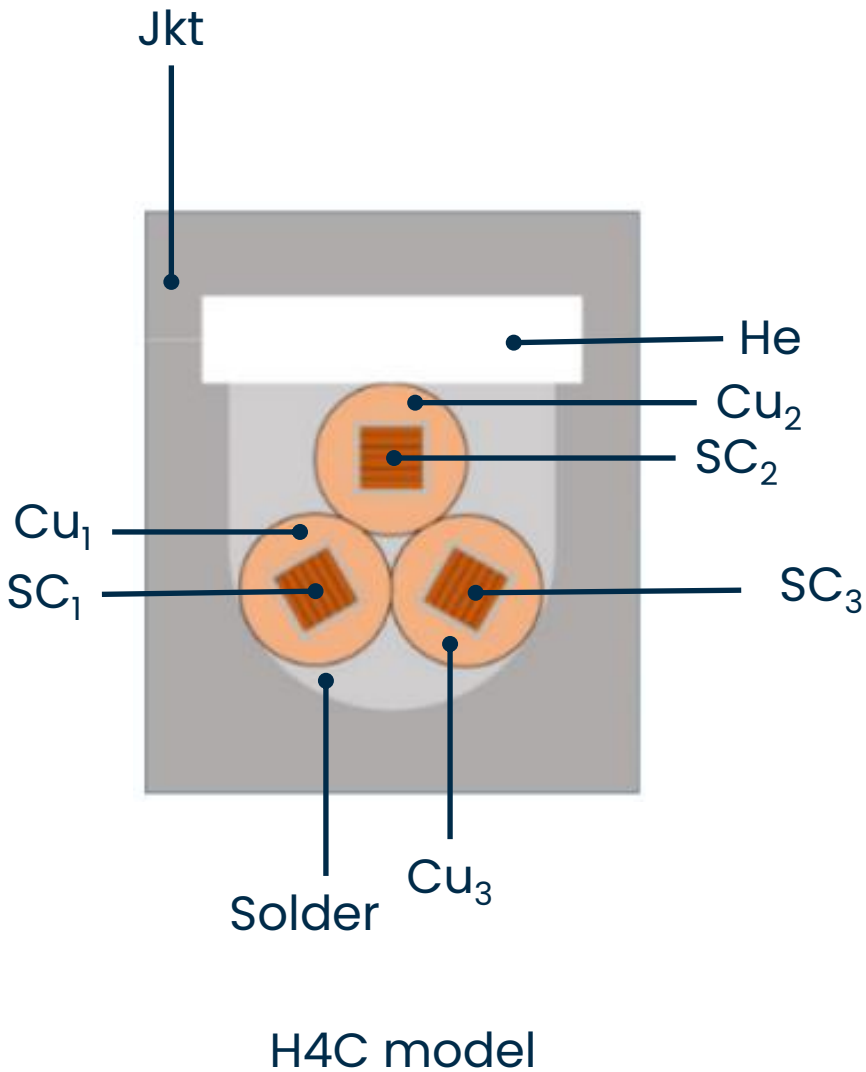
DC performance & NZPV

- $I_C(7\text{ T}, 7\text{ K}) = 14.8\text{ kA}$
- n-value = 14.4

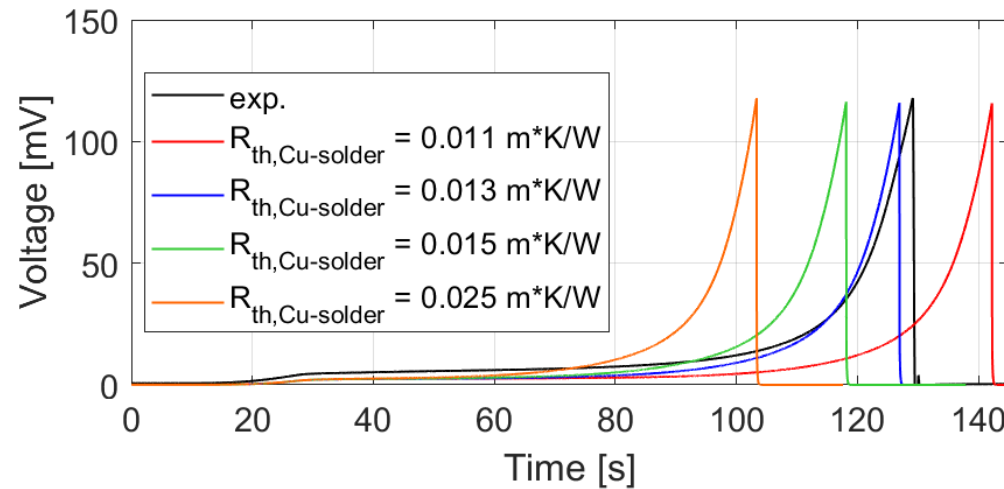
- NZPV is 5-10 mm/s (larger heat capacity due to solder wrt other REBCO conductors tested)
- Slow heating leads to much higher NZPV
- Low $J_{Cu} \rightarrow$ lower NZPV



Solder-filled H4C model & calibration



For $\gamma > 1.5$, no quench can be achieved, no matter the value of the thermal resistances

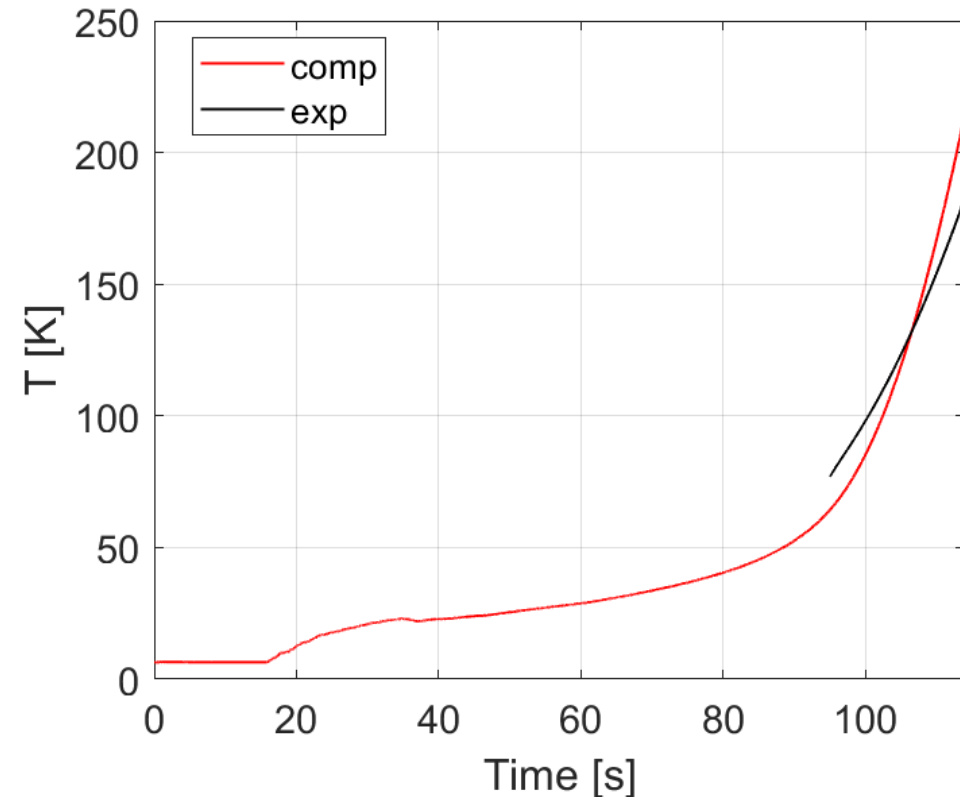
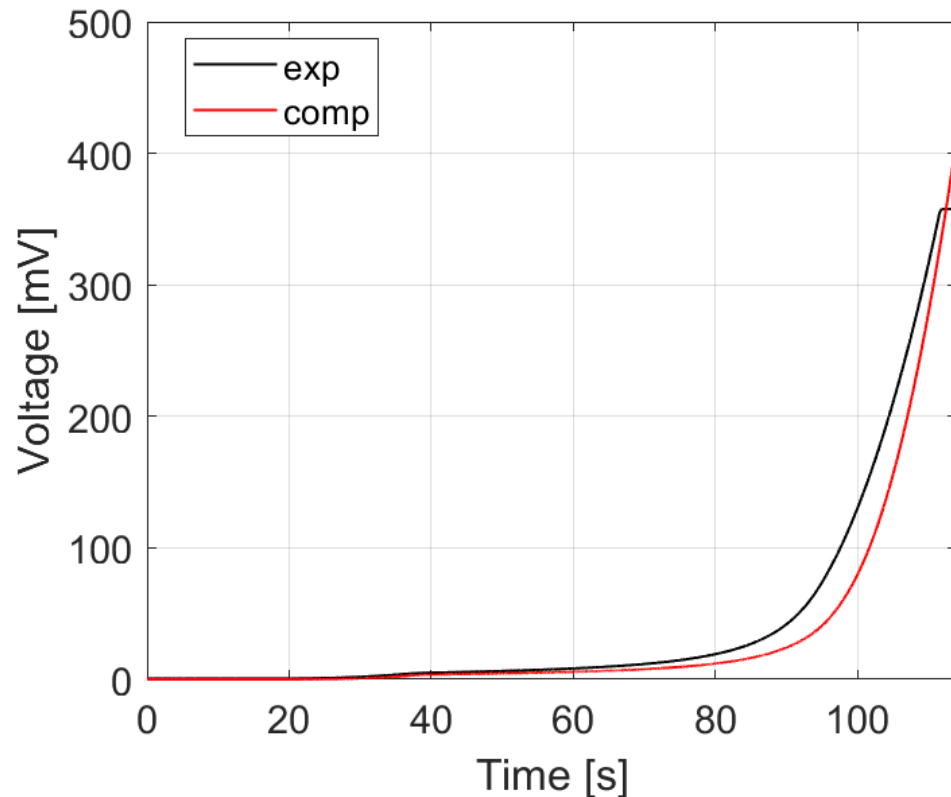


Multiple thermal resistances to be calibrated
 Here, fixed values of $R_{th,Cu-SS}$ (from previous conductors) and $R_{th,Solder-SS}$ and calibrate $R_{th,Cu-Solder}$

Solder-filled REBCO conductor – high J_{Cu} (I)

140809 (Solder-filled)
6.5 T, 15 kA
Dump at 130 K

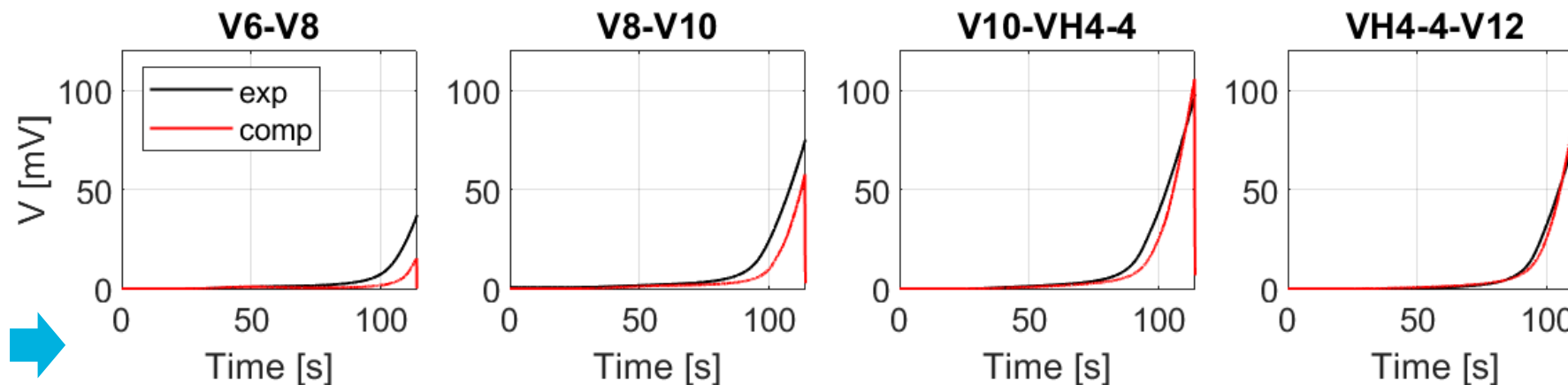
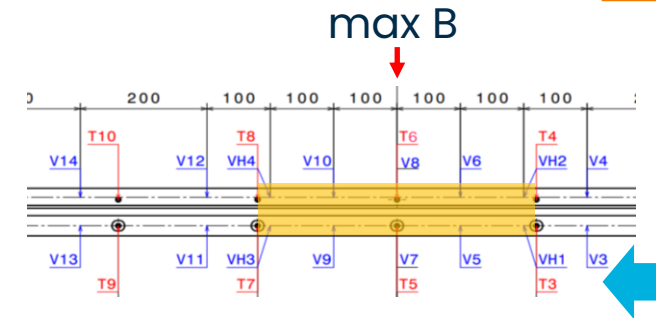
- Calibrated parameters are kept constant
- Slower rise (both in total V and hotspot temperature) below 500 mV, then faster than measured (as for the BSCCO conductor) → possible impact of different strategies for the discretization of the cross-section will be investigated



Solder-filled REBCO conductor – high J_{Cu} (II)

140809 (Solder-filled)
6.5 T, 15 kA
Dump at 130 K

- Quench propagation shifted towards the outlet is well captured by the model

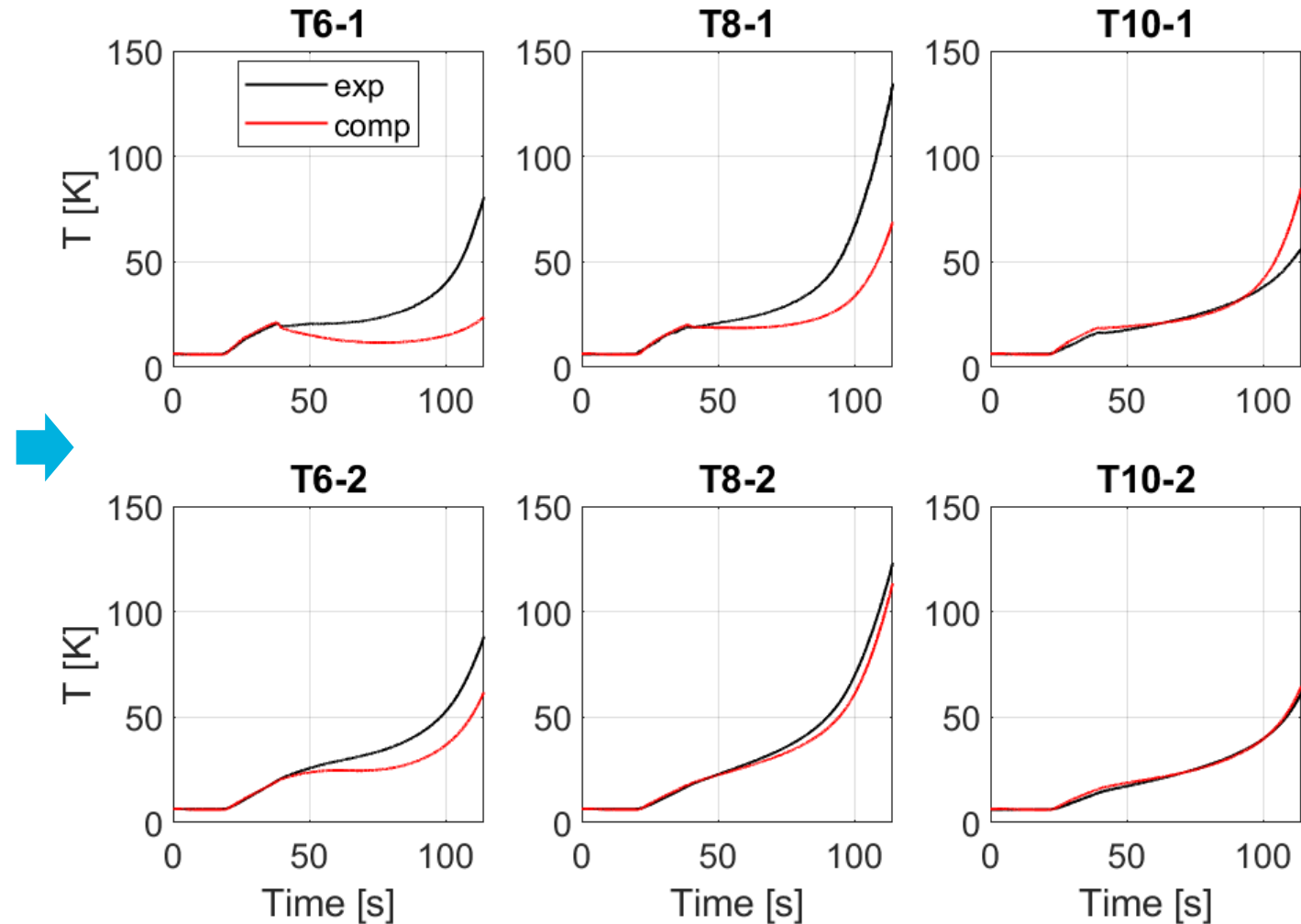


Solder-filled REBCO conductor – high J_{Cu} (III)

- Temperature rise close to the inlet does not match well with data, but high temperature region is better reproduced

140809 (Solder-filled)
6.5 T, 15 kA
Dump at **130 K**

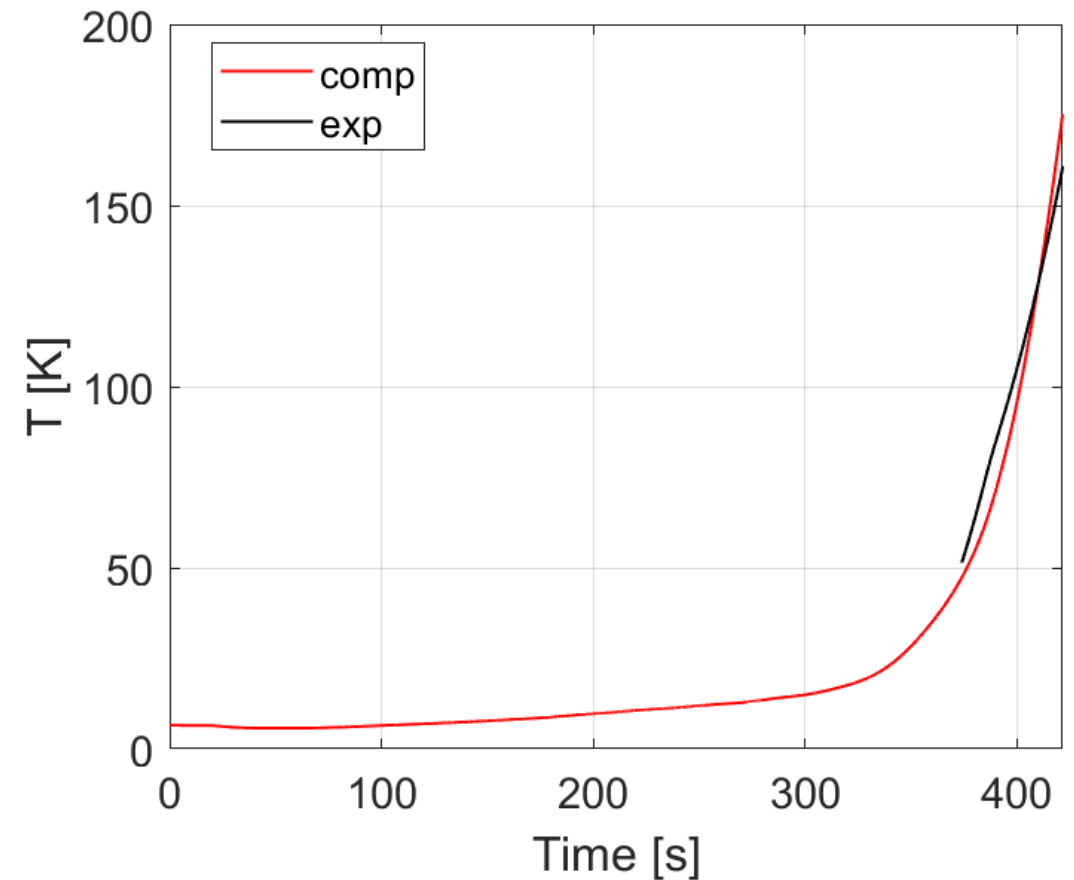
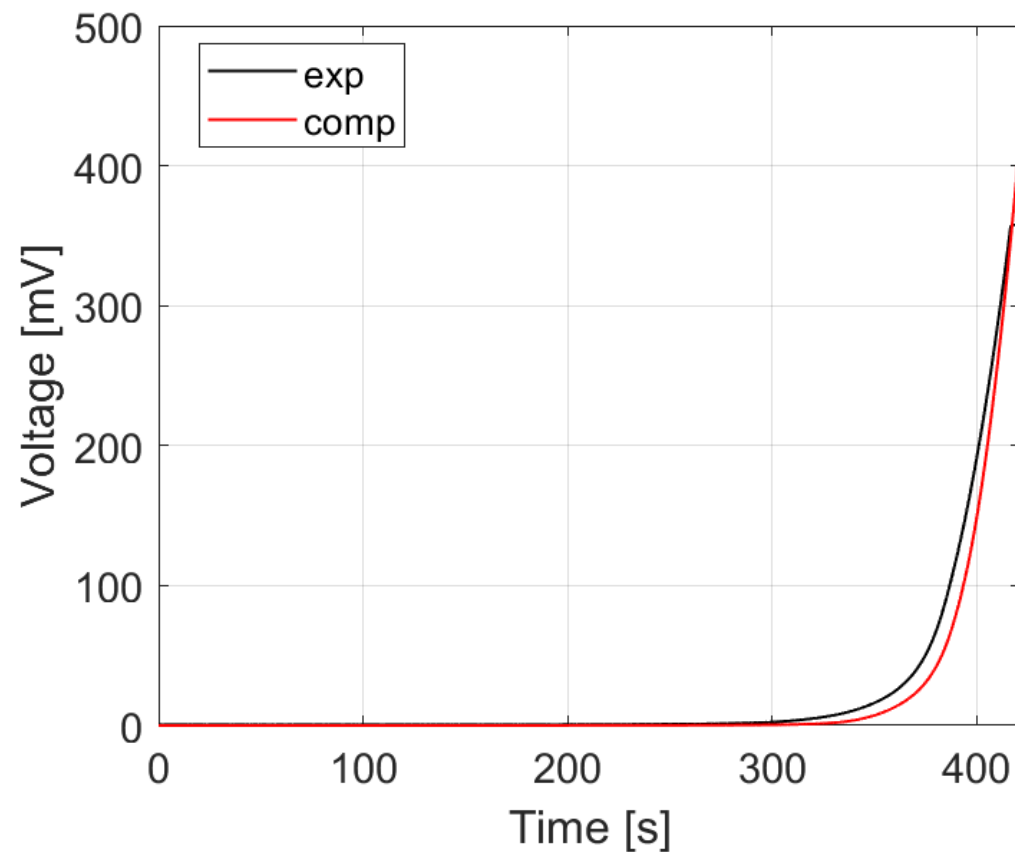
- Due to better coupling with jacket, T sensor on jacket gives $T \sim T_{He}$



Solder-filled REBCO conductor – low J_{Cu} (I)

- Calibrated parameters kept constant
- Here less evident differences than in high J_{Cu} case because slow heating and low J_{Cu} → slower transient

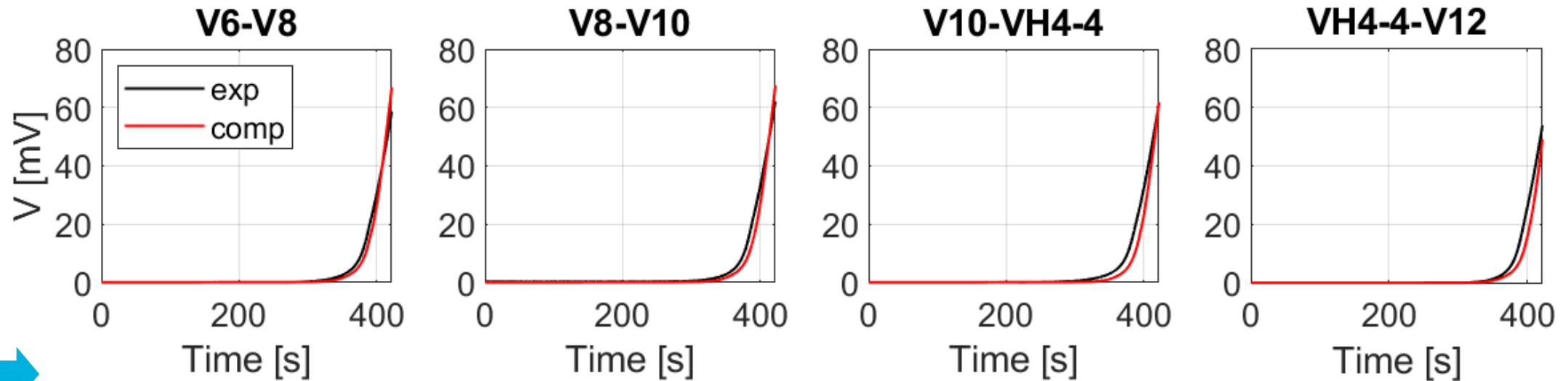
200801 (Solder-filled)
10.78 T, 11 kA
Dump at **130 K**



Solder-filled REBCO conductor – low J_{Cu} (II)

- Also locally, the agreement is better than high J_{Cu} case
- Currently looking into discretization of the cross-section (to more correctly account for thermal capacity)

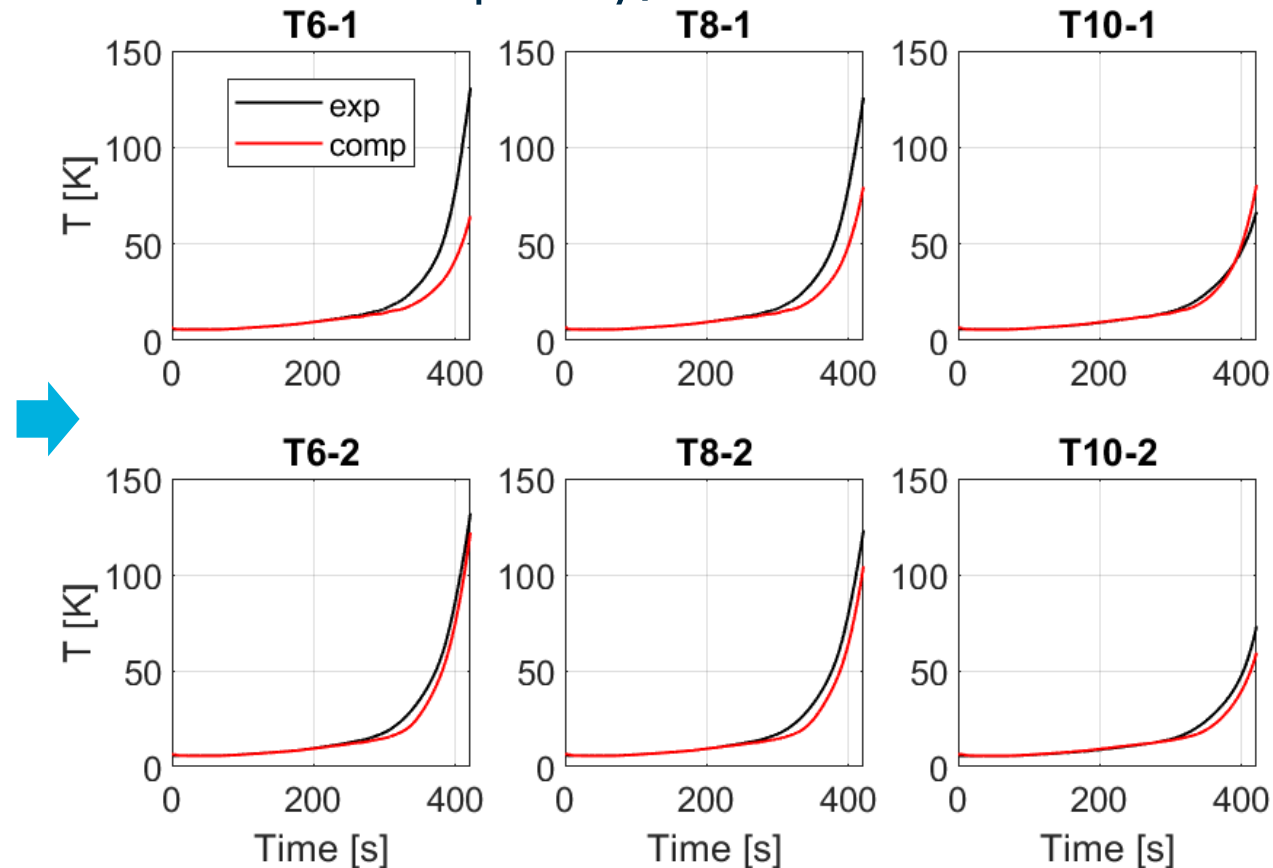
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Solder-filled REBCO conductor – low J_{Cu} (III)

- Also locally, the agreement is better than high J_{Cu} case
- Currently looking into discretization of the cross-section (to more correctly account for thermal capacity)

200801 (Solder-filled)
10.78 T, 11 kA
Dump at **130 K**



Conclusions and perspective

- The analysis of the NZPV shows that the “BSCCO” conductor behaves similarly to the “non-twisted” and “reference” ones (NZPV ~ 20–24 mm/s) while the “solder-filled” conductor has a lower NZPV (~ 5–10 mm/s)
- The H4C model of the “BSCCO” and “solder-filled” conductors have been developed and validated against global and local experimental data with a good agreement
- Accounting for twisting and distribution of J_C has strong impact on the agreement with the measured data
- Next steps:
 - different discretization strategies for the solder-filled conductor will be investigated
 - quench propagation in operating conditions relevant for fusion coils will be analyzed with the validated models

backup

Solder-filled conductor

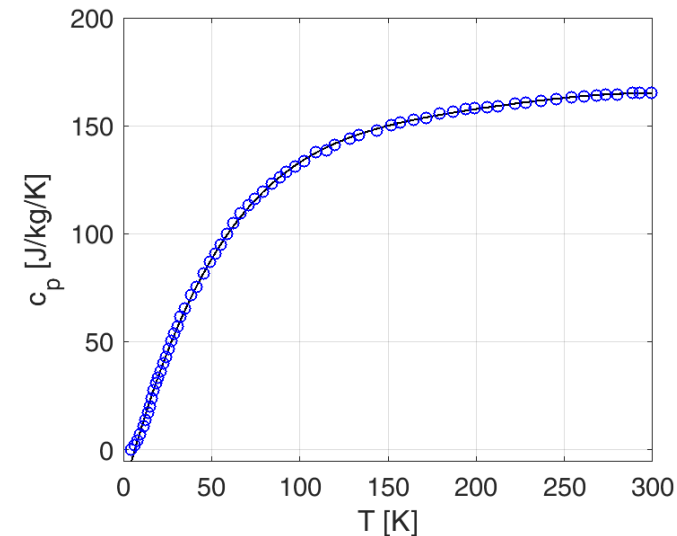
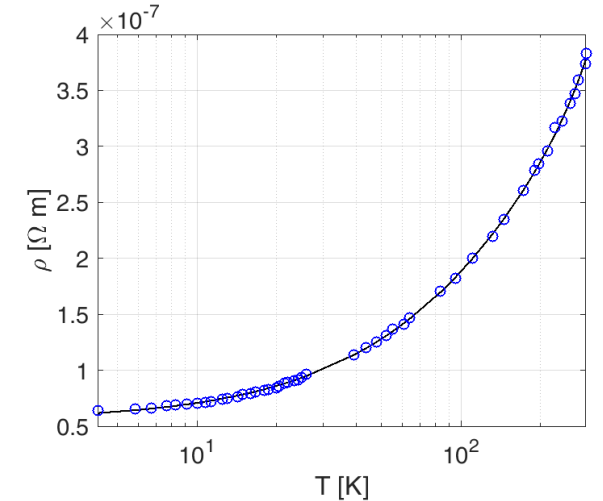
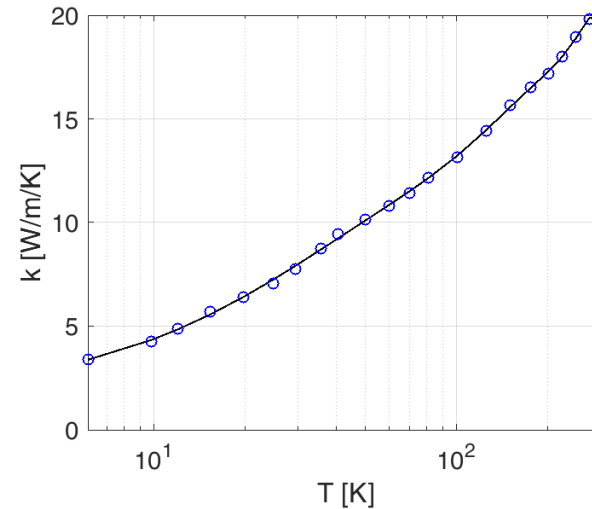
DC performance:

$$I_C(7\text{ T}, 7\text{ K}) = 14.8\text{ kA}$$

n-value = 14

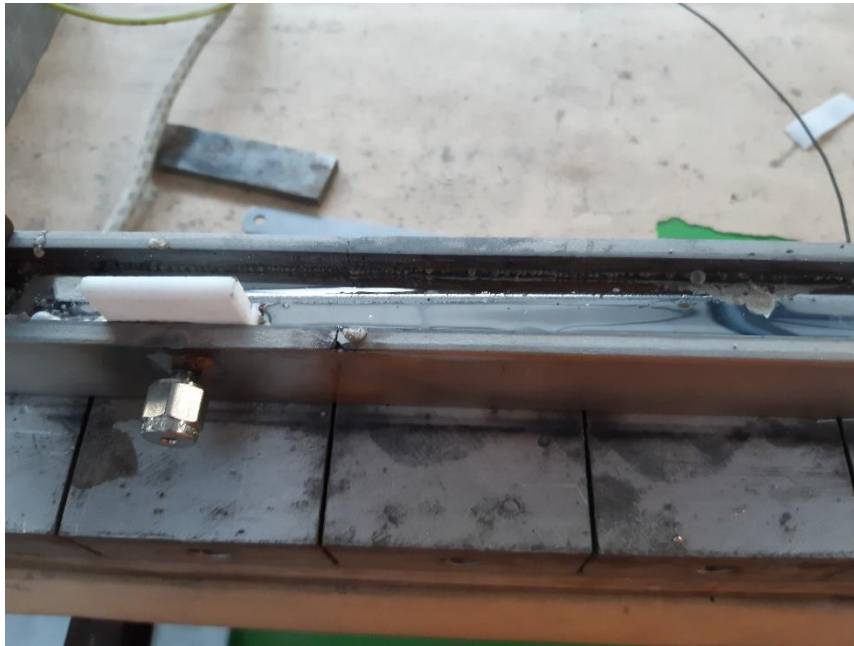
Building the model:

Solder thermophysical property
(Bi57Sn42Ag1, [O. Dicuonzo,
personal communication]) → data
at RT and 4.2 K, decent fit with
In67Bi33



Focus on T_{He} measurement (courtesy of O. Dicuonzo)

A possible reason could be linked to how He temperature is measured (which differs from all the others, perhaps measurement is altered by recirculation in the groove?)



We inserted a Teflon piece in front of the swagelock (through which the He sensor is inserted), that remained during the solder filling process

So we obtained a hole where the He could flow.

The jacket T sensor is placed on the opposite side of the helium channel

